

# Wideband IF Receiver Subsystem

<span id="page-0-3"></span>**4.3 mm × 5.0 mm WLCSP** 

# Data Sheet **[AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf)**

## <span id="page-0-0"></span>**FEATURES**

**High instantaneous dynamic range Noise figure (NF) as low as 13 dB Noise spectral density (NSD) as low as −159 dBFS/Hz IIP3 up to 36.9 dBm with spurious tones <−99 dBFS Tunable band-pass Σ-∆ analog-to-digital converter (ADC) 20 MHz to 160 MHz signal bandwidth 70 MHz to 450 MHz IF center frequency Configurable input full-scale level of −2 dBm to −14 dBm Easy to drive resistive IF input Gain flatness of 1 dB with under 0.5 dB out-of-band peaking Alias rejection greater than 50 dB 2.0 GSPS to 3.2 GSPS ADC clock rate On-chip PLL clock multiplier 16-bit I/Q rate up to 266 MSPS On-chip digital signal processing NCO and quadrature digital downconverter (QDDC) Selectable decimation factor of 12, 16, 24, and 32 Automatic gain control (AGC) support On-chip attenuator with 27 dB span in 1 dB steps Fast attenuator control via configurable AGC data port Peak detection flags with programmable thresholds Single or dual lane, JESD204B capable Low power consumption: 1.20 W 1.1 V and 2.5 V supply voltage TDD power saving up to 60%** 

## <span id="page-0-1"></span>**APPLICATIONS**

**Wideband cellular infrastructure equipment and repeaters Point-to-point microwave equipment Instrumentation Spectrum and communication analyzers** 

**Software defined radio** 

## <span id="page-0-2"></span>**GENERAL DESCRIPTION**

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf)<sup>1</sup> is a highly integrated IF subsystem that can digitize radio frequency (RF) bands up to 160 MHz in width centered on an intermediate frequency (IF) of 70 MHz to 450 MHz. Unlike traditional Nyquist IF sampling ADCs, the [AD6676 r](http://www.analog.com/AD6676?doc=AD6676.pdf)elies on a tunable band-pass Σ-Δ ADC with a high oversampling ratio to eliminate the need for band specific IF SAW filters and gain stages, resulting in significant simplification of the wideband radio receiver architecture. On-chip quadrature digital downconversion followed by selectable decimation filters reduces the complex data rate to a manageable rate between 62.5 MSPS to 266.7 MSPS. The 16-bit complex output data is transferred to the host via a single or dual lane JESD204B interface supporting line rates of up to 5.333 Gbps.



**FUNCTIONAL BLOCK DIAGRAM** 

1 This product is protected by U.S. and international patents.

### **Rev. D [Document Feedback](https://form.analog.com/Form_Pages/feedback/documentfeedback.aspx?doc=AD6676.pdf&product=AD6676&rev=D)**

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### **9/2015—Rev. 0 to Rev. A**



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**10/2014—Revision 0: Initial Version** 

The band-pass  $\Sigma$ - $\Delta$  ADC of th[e AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) which operates between 2.0 GHz to 3.2 GHz, provides exceptional instantaneous dynamic range and inherent antialiasing capability. Its in-band frequency response typically maintains better than 1 dB pass band flatness with out-of-band peaking better than 0.5 dB. An integrated digital peak detector enables the instantaneous signal power to be monitored over a wide band (shortly after digitization), thus providing AGC capability to cope quickly with large in-band or out-of-band blockers.

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) includes various AGC monitoring and control features along with an internal 27 dB step attenuator in 1 dB steps. A flexible AGC port with digital input/output pins allows fast control of the [AD6676 o](http://www.analog.com/AD6676?doc=AD6676.pdf)n-chip step attenuator and/or updates on the input signal via status flags. These features, along with the high instantaneous dynamic range, can significantly simplify AGC implementation compared to traditional narrow-band IF approaches that often require separate AGC capability for RF and IF protection.

In addition to reducing system complexity, the [AD6676 e](http://www.analog.com/AD6676?doc=AD6676.pdf)nables significant space and power consumption savings for next generation multiple input/multiple output (MIMO) receiver architectures. The [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s available in an  $8 \times 10$  ball array WLCSP package that is approximately 4.3 mm  $\times$  5.0 mm, with a JESD204B serial interface that allows simple interfacing to the host processor.

Its low power consumption of 1.2 W compares favorably to IF sampling ADCs with similar bandwidth (BW) and dynamic range capabilities even without considering the added power savings from the elimination of an entire IF strip. The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) features multichip synchronization that allows synchronization to within a fraction of an output data sample. For time-domain duplex (TDD) applications, th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) features a fast powerup/power-down mode that further reduces power consumption while still maintaining multichip synchronization. Power savings of up to 60% or 42% is achievable with recovery times of 11.5 µs or 2.5 µs, depending on the device configuration.

Auxiliary blocks include an on-chip PLL clock multiplier to generate the  $\Sigma$ - $\Delta$  ADC clock. For applications that require better phase noise performance, an external differential RF clock source may also be used. The SPI port programs numerous parameters of th[e AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) allowing the device to be optimized for a variety of applications.

The [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s available in an 80-ball WLCSP package with an optimized pinout that enables low cost printed circuit board (PCB) manufacturing. The device operates from a 1.1 V and 2.5 V supply with a total typical power consumption of 1.2 W at 3.2 GSPS operation. This product is protected by several United States patents. Contact Analog Devices, Inc., for further information.

## <span id="page-3-0"></span>**PRODUCT HIGHLIGHTS**

- 1. Industry leading dynamic range enables high performance, reconfigurable heterodyne (or direct sampling VHF) software defined radios with high AGC-free range.
- 2. Continuous time, band-pass Σ-Δ ADC supports IFs from 70 MHz to 450 MHz with IF signal bandwidths of up to 160 MHz and reduces IF filtering requirements.
- 3. The high instantaneous dynamic range and oversampling nature of the Σ-Δ ADC significantly reduces the IF filter complexity.
- 4. On-chip 27 dB digital attenuator with easy to drive resistive input simplifies interface to RF/IF components.
- 5. Small 4.3 mm  $\times$  5.0 mm package, simple interface, and integrated digital attenuator and clock synthesizer save PCB space.
- 6. Low input full-scale level of −2 dBm (or less) enables 3.3 V RF/IF component lineups at reduced P1dB and power.
- 7. Fast power saving mode supports TDD protocols.
- 8. Unique profile mode allows th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) to switch between up to four different ADC IF/BW configurations in 1 µs.

# <span id="page-4-0"></span>**SPECIFICATIONS**

 $\text{VDD1} = \text{VDDL} = \text{VDDC} = \text{VDDQ} = 1.1 \text{ V}, \text{VDDD} = \text{VDDHSI} = 1.1 \text{ V}, \text{VDD2} = 2.5 \text{ V}, \text{VDDIO} = 1.8 \text{ V}, \text{F}_{\text{IF}} = 250 \text{ MHz}, \text{BW} = 75 \text{ MHz}, \text{V} = 250 \text{ MHz}$  $F_{ADC} = 3.2$  GHz, attenuator = 0 dB, L± (inductor values) = 19 nH, maximum PIN\_0dBFS setting with IDAC1FS = 4 mA, fDATA\_IQ = 200 MSPS, shuffler enabled (every clock cycle) with default threshold of 5, unless otherwise noted.





<sup>1</sup> Extrapolated input power level is measured at the center of IF pass band that results in a 0 dBFS power level.

2 The overload level of the Σ-Δ ADC for a CW tone is guaranteed up to −2 dBFS back off from full scale but typically exceeds −1 dBFS. Input signals that have a higher

peak-to-average ratio (PAR) than a CW tone (PAR = 3 dB) must apply additional back off based on the difference in PAR.<br><sup>3</sup> The clock synthesizer reference divider (Register 0x2BB, Bits[7:6]) must be set to divide by 4 or  $4 f_{CLK} = 200 \text{ MHz}, F_{ADC} = 3.2 \text{ GHz}.$ 

 $^5$  Th[e AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s configured for recovery time of 11.5 µs with VSS2 generator/ digital data in standby (Register 0x150 = 0x40) and low power ADC state (Register 0x250 = 0x95).

## <span id="page-6-1"></span><span id="page-6-0"></span>**DIGITAL HIGH SPEED SERDES SPECIFICATIONS**

VDD1 = VDDL = VDDC = VDDQ = 1.1 V, VDDD = VDDHSI = 1.1 V, VDD2 = 2.5 V, VDDIO = 1.8 V, unless otherwise noted.





 $^1$  F<sub>DATA\_IQ</sub> corresponds to the complex output data rate (that is, F<sub>ADC</sub>/DEC\_FACTOR). Latency specification also includes ADC and digital filters delays. See Table 15 <sup>2</sup> The SYSREF± input requires an external differential resistor for proper termination.

<sup>3</sup> Set via Register 0x1E7, Bit 2, with CMOS being the default setting.<br><sup>4</sup> SYSREF± setup and hold times are defined with respect to the rising SYSREF± edge and rising clock edge. Positive setup time leads the clock edge. also lags the clock rising edge. Note that the hold time takes into consideration that the internal clock signal used to sample SYSREF operates at FADc/2; thus, SYSREF± must remain high for at least two FADC clock cycles.

## <span id="page-7-0"></span>**CLK± TO SYSREF± TIMING DIAGRAM**



Figure 2. SERDES CLK+ to SYSREF+ Timing

## <span id="page-7-1"></span>**DIGITAL CMOS INPUT/OUTPUT SPECIFICATIONS**

 $VDD1 = VDDL = VDDC = VDDQ = VDDD = VDDHSI = 1.1 V, VDD2 = 2.5 V, VDDIO = 1.8 V, unless otherwise noted.$ 

### **Table 3.**



1 This is the time required after a software or hardware reset until SPI access is available again.

# <span id="page-8-0"></span>ABSOLUTE MAXIMUM RATINGS

### **Table 4.**



Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

## <span id="page-8-1"></span>**THERMAL RESISTANCE**

Typical  $\theta_{JA}$  is specified for a 4-layer printed circuit board (PCB) with a solid ground plane in conformance to JESD51-9 2s2p. In addition, metal in direct contact with the package leads from metal traces, through holes, ground, and power planes reduces the value of  $\theta_{\rm JA}.$ 

### **Table 5. Thermal Resistance**



### <span id="page-8-2"></span>**ESD CAUTION**



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage<br>may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

# <span id="page-9-0"></span>PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



**Table 6. Pin Function Descriptions** 



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12348-610

12348-611

12348-612

# <span id="page-11-0"></span>TYPICAL PERFORMANCE CHARACTERISTICS

## <span id="page-11-1"></span>**NOMINAL PERFORMANCE FOR IF = 115 MHz (DIRECT SAMPLING VHF RECEIVER)**

 $F_{IF} = 115 \text{ MHz}$ , BW = 20 MHz,  $F_{ADC} = 2.4 \text{ GHz}$ , attenuator = 0 dB,  $L_{EXT} = 100 \text{ nH}$ , maximum PIN\_0dBFS setting,  $f_{DATA\_IQ} = 75 \text{ MSPS}$ , nominal supplies, shuffler enabled (every 4 clock cycles), with default threshold settings, unless otherwise noted.



Figure 9. Integrated In-Band Noise (IBN) in IF Pass Band Region of 10 MHz vs. Swept Single Tone Input Power with CW at 130 MHz



Figure 10. Worst Spur Falling in 75 MHz Pass Band for Swept CW from 77.5 MHz to 152.5 MHz





Figure 13. Worst Pass Band Spur with Swept CW from 77.5 MHz to 150 MHz, over  $P_{IN} = -1$  dBFS,  $-6$  dBFS,  $-12$  dBFS, and  $-18$  dBFS





### <span id="page-13-0"></span>**NOMINAL PERFORMANCE FOR IF = 140 MHz (µW POINT-TO-POINT RECEIVERS)**

 $F_{IF}$  = 140 MHz, BW = 56 MHz or 112 MHz,  $F_{ADC}$  = 3.2 GHz, attenuator = 0 dB, L<sub>EXT</sub> = 43 nH, maximum PIN\_0dBFS setting,  $f_{DATA\_IQ}$  = 200 MSPS, nominal supplies, shuffler enabled (every clock cycle), with default threshold settings, unless otherwise noted.







Figure 17. NSD with No Signal, IBN = 112 MHz and 56 MHz



Figure 18. Spectral Plot of CW Interferer Dynamic Range for QAM1024, Channel BW = 14 MHz at Sensitivity Level with CW Interferer 30 dB Higher at 35 MHz Offset





Figure 20. IBN vs. Swept Single Tone Input Power over Channel BW = 7 MHz, 14 MHz, 28 MHz, and 56 MHz, CW Blocker at 350 MHz



Figure 21. Two-Tone IMD Performance  $(f_1 = 137.5 \text{ MHz}, f_2 = 142.5 \text{ MHz})$ 

## <span id="page-14-0"></span>**NOMINAL PERFORMANCE FOR IF = 181 MHz (WIRELESS INFRASTRUCTURE RECEIVER)**

 $F_{IF}$  = 181 MHz, BW = 75 MHz,  $F_{ADC}$  = 2.94912 GHz, attenuator = 0 dB, L<sub>EXT</sub> = 43 nH, maximum PIN\_0dBFS setting, f<sub>DATA\_IQ</sub> = 122.88 MSPS, shuffler enabled (every clock cycle), with default threshold settings, unless otherwise noted.



Figure 22. IF Pass Band Flatness (Includes Digital Filter)



Figure 23. NSD With and Without Full-Scale CW at 210 MHz



Figure 24. Spectral Plot of IF Pass Band Region with −1 dBFS CW at 220 MHz



Figure 25. Wideband Frequency Response (Before Digital Filter)



Figure 26. NSD vs. CW Input Power, CW = 210 MHz (NSD Measured at 181 MHz as well as 146 MHz and 216 MHz Band Edges)



Figure 27. IBN in IF Pass Band Region (BW = 75 MHz) vs. Swept Single Tone Input Power with CW at 220 MHz



Figure 28. Worst Spur Falling in 75 MHz Pass Band for Swept CW from 122.88 MHz to 245.76 MHz





Figure 31. Swept Worst Pass Band Spur with CW Swept from 122.88 MHz to 245.76 MHz, over P<sub>IN</sub> = −1 dBFS, −6 dBFS, −12 dBFS, and −18 dBFS



Figure 33. Swept Two-Tone Worst IMD3 vs. Frequency over Pass Band (∆f = 5 MHz for Two Tones, P<sub>IN</sub> = -8 dBFS, -14 dBFS, and -20 dBFS)

### <span id="page-16-0"></span>**NOMINAL PERFORMANCE FOR IF = 250 MHz AND BW = 75 MHz**

 $F_{IF} = 250$  MHz, BW = 75 MHz,  $F_{ADC} = 3.2$  GHz, attenuator = 0 dB,  $L_{EXT} = 19$  nH, maximum PIN\_0dBFS setting,  $f_{DATA\_IQ} = 200$  MSPS, nominal supplies, shuffler enabled (every clock cycle), with default threshold settings, unless otherwise noted.



Figure 34. IF Pass Band Flatness (Includes Digital Filter)



Figure 35. NSD With and Without Full-Scale CW at 243 MHz



Figure 36. Spectral Plot of IF Pass Band Region with −1 dBFS CW at 288 MHz



Figure 37. Wideband Frequency Response (Before Digital Filter)



Figure 38. NSD vs. CW Input Power, CW at 243 MHz (NSD Measured at 250 MHz as well as 212.5 MHz and 287.5 MHz Band Edges)



Figure 39. IBN in the Pass Band Region (BW = 75 MHz) vs. Swept Single Tone Input Power with CW at 288 MHz



Figure 40. Worst Spur Falling in 75 MHz Pass Band for Swept CW from 150 MHz to 300 MHz











## <span id="page-18-0"></span>**NOMINAL PERFORMANCE FOR IF = 350 MHZ AND BW = 160 MHZ**

 $F_{IF}$  = 350 MHz, BW = 160 MHz,  $F_{ADC}$  = 3.2 GHz, attenuator = 0 dB, L $_{EXT}$  = 10 nH, maximum PIN\_0dBFS setting,  $f_{DATA\_IQ}$  = 266.7 MSPS, shuffler enabled (every clock cycle), with default threshold settings, unless otherwise noted.



Figure 46. IF Pass Band Flatness (Includes Digital Filter)



Figure 47. NSD With and Without Full-Scale CW at 355 MHz



Figure 48. Spectral Plot of IF Pass Band Region with −1 dBFS CW at 431 MHz



Figure 49. Wideband Frequency Response (Before Digital Filter)



Figure 50. NSD vs. CW Input Power, CW at 355 MHz (NSD Measured at 350 MHz as well as 350 MHz and 400 MHz Band Edges)



Figure 51. IBN in IF Pass Band Region (BW = 160 MHz) vs. Swept Single Tone Input Power with CW at 431 MHz



Figure 52. Worst Spur Falling in 160 MHz Pass Band for Swept CW from 217 MHz to 484 MHz



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**ñ80**

Figure 55. Swept Worst Pass Band Spur with CW Swept from 217 MHz to 484 MHz  $over P_{IN} = -1$  dBFS,  $-6$  dBFS,  $-12$  dBFS, and  $-18$  dBFS



Figure 57. Swept Two-Tone Worst IMD3 vs. Frequency over Pass Band  $(Δf = 5 MHz for Two Tones, P<sub>IN</sub> = −8 dBFS, −14 dBFS, and −20 dBFS)$ 

# <span id="page-20-0"></span>EQUIVALENT CIRCUITS



Figure 58. Equivalent CSB or SCLK Input Circuit



Figure 59. Equivalent Analog Input



Figure 60. Equivalent Clock Input Circuit



Figure 61. Equivalent SYSREF± Input



Figure 62. Equivalent SDIO or AGCx Input/Output Circuit



Figure 63. Equivalent RESETB Input Circuit



Figure 64. Equivalent SYNCINB± Input



Figure 65. Digital CML Output Circuit

# <span id="page-21-0"></span>**TERMINOLOGY**

### **Noise Figure (NF)**

NF is the degradation in SNR performance (in dB) of an input signal having a noise density of −174 dBm/Hz after it passes through a component or system. Mathematically,

 $NF = 10 \times log(SNR<sub>IN</sub>/SNR<sub>OUT</sub>)$ 

The noise figure of th[e AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s determined by the equation

 $NF = P_{IN} - (10 \times \log(BW)) - (-174.0 \text{ dBm/Hz}) - SNR$ 

### where:

 $P_{IN}$  is the input power of an unmodulated carrier. BW is the noise measurement bandwidth.

 $-174.0$  dBm/Hz is the thermal noise floor at 290 K.

SNR is the measured signal-to-noise ratio in dB of th[e AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf)

Note that  $P_{IN}$  is set to a low level (that is, <-40 dBm) to minimize any degradation in measured SNR due to phase noise from either the input signal or  $\Sigma$ - $\Delta$  ADC clock source.

### **Noise Spectral Density (NSD)**

NSD is the noise power normalized to 1 Hz bandwidth (at a particular frequency) relative to the full scale of the ADC (dBFS) and hence is given in units of dBFS/Hz. Th[e AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) being a Σ-Δ ADC, displays a uneven NSD across its IF pass band. Both the worst-case NSD as well as NSD at the pass band center are reported. Note that NSD is calculated from the IBN measured over a 5 MHz bandwidth.

### **In-Band Noise (IBN)**

IBN is the integrated noise power measured over a user defined bandwidth relative to the full scale of the ADC (dBFS). This bandwidth is typically equal to the IF pass band setting (BW) of the [AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) unless otherwise noted.

### **Input Second-Order Intercept (IIP2)**

IIP2 is a figure of merit used to quantify the second-order intermodulation distortion (IMD2) of a component or system. Two equal amplitude unmodulated carriers at specified frequencies ( $f_1$  and  $f_2$ ) injected into a nonlinear system exhibiting second-order nonlinearities produce IMD components at  $f_1 - f_2$ and  $f_1 + f_2$ . For the [AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) the two frequencies are situated at ½ the IF frequency (with a 2 MHz offset) at a power level corresponding to −6 dBFS at the IF center frequency with only the intermodulation term at  $f_1 + f_2$  considered. IIP2 is the extrapolated tone power at which the intermodulation terms and the input tones have equal amplitude.

 $IIP2 = P<sub>IN</sub> - IMD2$ 

### **Input Third-Order Intercept (IIP3)**

IIP3 is a figure of merit used to quantify the third-order intermodulation distortion (IMD3) of a component or system. Two equal amplitude unmodulated carriers at specified frequencies  $(f_1$  and  $f_2$ ) injected into a nonlinear system exhibiting third-order nonlinearities produce IMD components at 2  $f_1 - f_2$  and 2  $f_2 - f_1$ . IIP3 is the extrapolated tone power at which the intermodulation terms and the input tones have equal amplitude.

$$
IIP3=P_{I\!N}-IMD3/2
$$

Note that the third-order IMD performance of an ADC does not necessarily follow the 3:1 rule that is typical of RF/IF linear devices. IMD performance is dependent on the dual tone frequencies, signal input levels, and ADC clock rate.

### **Worst In-Band Spur (SFDR)**

Worst in-band spur is the worst spur falling in the IF pass band relative to the full scale of the ADC (dBFS) when a single tone with defined power level is stepped (typically 1 MHz increments) across a user defined frequency range. Note that this worst spur can often be an image (or clock) related spur depending on the IF, BW, and IQ output data rate setting of th[e AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)nd on the sweep range.

### **Signal Transfer Function (STF)**

STF is the frequency response of the output signal of the ADC relative to a swept single tone at its input. The STF presented for differen[t AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)etup conditions in th[e Typical Performance](#page-11-0)  [Characteristics s](#page-11-0)ection shows the STF over the IF pass band after the digital filter to highlight pass band flatness. The wideband STF response is measured before the digital filter to highlight the pass band response of the [AD6676 Σ](http://www.analog.com/AD6676?doc=AD6676.pdf)-Δ ADC.

## <span id="page-22-1"></span><span id="page-22-0"></span>THEORY OF OPERATION **OVERVIEW**

The [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s a highly integrated and flexible IF subsystem capable of digitizing IF signals. The ability to tune the IF frequency and bandwidth allows the Σ-Δ ADC to be optimized for different applications while trading off bandwidth for dynamic range. To facilitate its evaluation and design in, a software tool that is part of the [AD6676EBZ d](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)evelopment platform must be used to configure and evaluate the device. This tool saves the SPI initialization and configuration sequence to a file for later use. A screenshot of the GUI front panel (se[e Figure 66\)](#page-22-2) shows the different user specified application parameters that configure the [AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) The following discussion provides more insight into the device operation and how these application parameters affect performance.

<b>FADC [GHz]</b>	3.2	L [nH]	19		Margin(MHz)	[550]
FIF IMHZI	300	Atten, [dB]	o			
<b>EW [MHz]</b>	100	<b>PIN DdBFS [dBm]</b>				
V Use Synth (MHz)	<b>MARCHE</b> 200	Output Mode 3 - Deci-16		٠		
Is 3 Wire SPI		Sample Size 32768	ç.			
<b>Flash Shuffle</b> Shift Every 1 Clk		<b>JESD Lanes</b> Double				

<span id="page-22-2"></span>Figure 66. Screenshot o[f AD6676 G](http://www.analog.com/AD6676?doc=AD6676.pdf)UI Software Tool that Facilitates Device Configuration and Evaluation

A functional block diagram of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s show[n Figure 67.](#page-22-3)  The focal point of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s its continuous time, band-pass Σ-Δ ADC that operates with a clock rate between 2.0 GHz and 3.2 GHz. An on-chip controller configures the Σ-Δ ADC based on the user specified application parameters. The Σ-Δ ADC provides exceptional dynamic range and pass band flatness within the desired IF span while limiting out-of-band peaking to less than 0.5 dB. An on-chip clock synthesizer supplies a 2.94 GHz to 3.2 GHz Σ-Δ ADC clock. Alternatively, an external clock can be supplied for lower clock rates or improved phase noise performance.

On-chip digital signal processing blocks include a quadrature digital downconverter (QDDC) followed by selectable decimation filters supporting decimation factors of 12, 16, 24, or 32. The QDDC performs a complex shift of the desired IF pass band such that it is centered about dc, that is, zero IF. Cascaded decimation filters remove the inherent out-of-band noise of the ADC along with any other out-of-band signal content such that the 16-bit complex IQ data is reduced to a more manageable data rate for transfer to the host via a single or dual lane JESD204B interface supporting up to 5.333 Gbps lane rates.

Th[e AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)lso includes features for AGC support and/or levelplanning optimization. AGC support includes the ability to monitor peak power at the  $\Sigma$ - $\Delta$  ADC output or rms power after the first internal decimation stage. The host can initiate fast AGC action by configuring various flags whose status are made available on the AGC4 to AGC1 pins. Flags can be set with programmable thresholds indicating whether the signal level is above or below a defined level. A 27 dB attenuator with a step size of 1 dB is available for IF AGC control or level planning optimization during initial system calibration. Alternatively, the nominal 0 dBFS full-scale input power level (PIN\_0dBFS) of −2 dBm can be reduced by up to 12 dB thus further reducing the RF/IF gain requirements. The SPI programs numerous parameters of the [AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) allowing the device to be optimized for a variety of applications.

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Figure 68. Simplified Single-Ended Representation of the Band-Pass Σ-Δ ADC Modulator

## <span id="page-23-1"></span><span id="page-23-0"></span>**BAND-PASS Σ-∆ ADC ARCHITECTURE**

[Figure 68 s](#page-23-1)hows a simplified single-ended representation of the [AD6676 b](http://www.analog.com/AD6676?doc=AD6676.pdf)and-pass Σ-Δ ADC. It is a sixth-order modulator consisting of three cascaded second-order continuous-time resonators with feedback DACs and an oversampling quantizer. The first resonator (RESON1) is based on a LC tank with its resonant frequency tuned via CARRAY to the IF center while the second and third resonators (RESON2 and RESON3) are active RC-based with their resonant frequencies tuned to frequencies offset symmetrically about the IF. These resonant frequencies correspond to the zero locations of the  $\Sigma$ - $\Delta$  ADC quantization noise and are set according to the user defined IF frequency and bandwidth.

A 17-level flash ADC oversamples the analog output of RESON3 with the digital output of the flash ADC feeding back to each of the resonators via current mode DACs (IDACx). Note that because the ADC thermometer code output can range from −8 to +8, it is represented by five bits that are passed to the [AD6676 d](http://www.analog.com/AD6676?doc=AD6676.pdf)igital path. The IDAC1 full-scale current setting (IDAC1<sub>FS</sub>) sets the maximum full-scale input power level (PIN\_0DBFS). The full-scale settings of the other IDACs set the pole location of the modulator to achieve a flat pass band response. Lastly, a programmable shuffler follows the flash ADC to improve the linearity performance of the [AD6676 u](http://www.analog.com/AD6676?doc=AD6676.pdf)nder large signal conditions.

The tunable nature of the  $\Sigma$ - $\Delta$  ADC is a result of the full-scale current of the feedback DACs, as well as the conductances (G) and capacitances (C) associated with each resonator. The value of these programmable components are calculated from the user specified application parameters listed i[n Table 7.](#page-23-2) The impact of each of these parameters on the performance of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s described in subsequent sections.

<span id="page-23-2"></span>**Table 7. List of User Specified Application Parameters That Determine the Σ-Δ ADC Internal Settings** 

<b>Application</b>		
<b>Parameter</b>	<b>Description</b>	<b>SPI Register(s)</b>
Fir	IF center frequency in MHz	0x102, 0x103
<b>BW</b>	IF pass band bandwidth in MHz	0x104, 0x105
<b>FADC</b>	$\Sigma$ - $\Delta$ ADC clock rate in MHz	0x100, 0x101
LEXT	External inductor value in nH	0x106
<b>MRGN</b>	Margin offset to set resonator frequency in MHz	0x107 to 0x109
<b>IDAC1<sub>FS</sub></b>	Full-scale current of IDAC1 that sets PIN 0dBFS level	0x10A

The on-chip controller is used only during device initialization and performs the following tasks:

- Power-up negative regulator (used by IDACs)
- Calibrate RESON1 and 17-level flash ADC
- Tune Σ-Δ ADC based on user input parameters
- Set up PLL used by JESD204B PHY

After device initialization, the on-chip controller is disabled; it is not used during normal device operation.

### **Signal and Noise Transfer Functions**

The frequency domain response of a  $\Sigma$ - $\Delta$  ADC is defined by its signal and noise transfer functions (STF and NTF)[. Figure 69](#page-24-0)  shows a simplified feedback model of a  $\Sigma$ - $\Delta$  modulator with the ADC quantization error modeled as an additive noise source (E) after the loop filter (H). The STF is the frequency response of the output signal (V) relative to a swept single tone at its input (U) while the NTF is the frequency response of the ADC quantization noise (that is, V/E) that undergoes noise shaping due to of the loop filter of the ADC. Note that the ADC and DACs within the feedback loop operate at a much higher clock rate than a traditional open-loop ADC in which only the Nyquist criterion must be satisfied ( $F_{ADC} = 2 \times BW$ ).

The oversampling ratio (OSR) is a key parameter of any  $\Sigma$ - $\Delta$ ADC and is defined as follows:

$$
OSR = F_{ADC}/(2 \times BW) \tag{1}
$$



<span id="page-24-0"></span>Figure 69. Simplified Model of a Σ-Δ ADC Showing Origins of STF and NTF

In the case of th[e AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) the loop filter consists of three cascaded resonators to implement a sixth-order band-pass response, thus allowing the oversampling ratio of the [AD6676 t](http://www.analog.com/AD6676?doc=AD6676.pdf)o be kept to moderate levels  $(\geq 10)$  such that useable bandwidths of up to 160 MHz can be realized. The loop filter utilizes a feedback architecture so that the STF has minimal out-of-band gain peaking while the NTF suppresses the in-band quantization noise[. Figure 70](#page-24-1) shows an example of the STF and the shaped noise of the Σ-Δ ADC when it is configured for BW = 80 MHz,  $F_{IF}$  = 300 MHz, and  $F_{ADC}$  = 3.2 GHz. Note that the NSD near  $F_{IF}$ is much lower than the NSD elsewhere and that the STF is quite broadband.



<span id="page-24-1"></span>[Figure 71 f](#page-24-2)ocuses on the IF pass band region to compare the measured vs. ideal shaped noise with the theoretical NSD curve accounting only for the ideal ADC quantization effect. The resonator zero locations are highlighted on the theoretical trace and are recognizable in the measured response. Note that the region with the lowest NSD performance or the deepest notch is always centered about the  $F_{IF}$  setting. This is because the gain of RESON1 peaks at  $F_{IF}$  and the noise from stages which follow RESON1 is input referred by dividing by the gain of RESON1.



<span id="page-24-2"></span>Unlike conventional ADCs, the NSD of a  $\Sigma$ - $\Delta$  ADC is not flat due to its frequency dependent loop filter, H(s), which shapes the quantization noise as well as various other noise sources. Because the Σ-Δ ADC is highly programmable, its NSD can be optimized for the user specified application parameter settings. In general, the NSD performance varies based on the application parameter settings in the following ways:

- Operating with a high oversampling ratio (OSR > 20) results in the lowest and flattest NSD performance. This is because the resonant frequencies (or zero locations) associated with RESON1, RESON2, and RESON3 are close together when the oversampling ratio is high thereby reducing the quantization noise to the point where thermal noise from the first stage IDAC1 dominates.
- Operating at reduced oversampling ratio (oversampling ratio < 20) causes the quantization noise contribution to become more significant, causing humps to appear in the NSD. Bumpiness in the NSD occurs because the resonant frequencies associated RESON2 and RESON3 are further offset from RESON1 to accommodate the increase in BW; therefore, resulting in less overall loop gain to suppress this increasingly dominant noise source. The effect of different oversampling ratios on the NSD is shown in [Figure 72.](#page-25-0)
- Operating at a lower  $F_{IF}$  while keeping the same oversampling ratio results in degraded NSD performance at the pass band edges, as shown in [Figure 73.](#page-25-1)



<span id="page-25-0"></span>Figure 72. NSD vs. Oversampling Ratio ( $F_{IF}$  = 300 MHz,  $F_{ADC}$  = 3.2 GHz,  $L_{EXT}$  = 19 nH)



<span id="page-25-1"></span>100 MHz to 300 MHz with Fixed Oversampling Ratio = 16  $(BW = 100$  MHz,  $F_{ADC} = 3.2$  GHz)

The impact of a uneven NSD profile on a particular application depends on the bandwidth and modulation characteristics of the IF signal being digitized and demodulated. For example, a multimode software defined radio containing narrow-band carriers situated anywhere across the pass band must consider the NSD performance at the highest levels across the pass band because this represents the worst-case NSD when calculating the in-band noise for a narrow-band signal in this region. Conversely, a single wideband QAM signal falling at the center of the IF pass band benefits from excellent in-band noise performance because the NSD remains the lowest in this region. Note that the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) specified NF is measured in the region where its NSD is highest.

### **STF and NTF Repeatability**

After the application parameters have been determined, the STF and NTF characteristics of the [AD6676 r](http://www.analog.com/AD6676?doc=AD6676.pdf)emain repeatable and stable over temperature and among devices. The on-chip calibration performed during the power-up initialization phase reduces the device-to-device variation that may otherwise exist due to tolerances associated with the device process or the external inductor, LEXT. It is worth noting that that the small variation in STF and NTF that does exist is likely to be less than traditional receiver solutions employing low oversampling ADCs with aggressive high order LC antialiasing filters. L and C component tolerances as well as variation in active device source and load impedances must be considered in the Monte Carlo analysis.

The following application parameters were used to demonstrate STF and NTF repeatability:  $f_{CLK} = 3.2$  GHz,  $F_{IF} = 250$  MHz, BW = 75 MHz,  $L_{EXT}$  = 19 nH, IDAC1<sub>FS</sub> = 4 mA, MRGN = default. [Figure 74 a](#page-25-2)nd [Figure 75](#page-25-3) demonstrate the repeatability and temperature stability of the STF and NTF responses of single devices for five consecutive power-up initialization operations in which the device is calibrated at 25°C and then allowed to drift to −40°C and +85°C.



<span id="page-25-2"></span>Figure 74. STF Variation over Temperature for a Single Device for Five Consecutive Power-Up Initialization Operations



<span id="page-25-3"></span>Figure 75. NTF Variation over Temperature for a Single Device for Five Consecutive Power-Up Initialization Operations

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### **Σ-∆ ADC Overload and Recovery**

The  $\Sigma$ - $\Delta$  ADC is a sixth-order modulator employing negative feedback to reduce the noise contribution of its internal quantizer. Like any ADC, the quantizer is driven into overload under large signal conditions, causing its output to be a poor representation of its input. However, unlike traditional ADCs that operate in open-loop, a Σ-Δ ADC can be driven into overload with signals slightly below its 0 dBFS full-scale input level and the feedback loop can become unstable and may not return to normal operation when the overload condition is removed. A typical unstable Σ-Δ ADC produces a digital output that varies between plus or minus full scale. Th[e AD6676 e](http://www.analog.com/AD6676?doc=AD6676.pdf)mploys several techniques to solve these problems.

First, to make the no overload range with continuous wave tones approach levels near 0 dBFS, the [AD6676 u](http://www.analog.com/AD6676?doc=AD6676.pdf)ses a 5-bit quantizer. The [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s specified to remain unconditionally stable for continuous wave levels below −2 dBFS over its full operation range, with a typical overload level of −0.5 dBFS. In practice, the large signal waveform characteristics that determine the occurrence and duration of its peaks affect the overload threshold. A continuous wave tone is close to the worst-case scenario for overload because the peak levels have the highest probability of occurrence. Alternatively, a signal that has a much higher crest factor and a more Gaussian-like histogram is less likely to cause overload due to the short duration of its peak excursions. For this reason, for systems employing AGC, consider the waveform characteristics when setting the AGC threshold.

Second, to ensure that the ADC does not become stuck in a self sustaining overload condition, the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)ncludes the means to detect overload, reset the Σ-Δ ADC, and quickly return it to normal operation. An overload condition is declared if more than five out of eight samples from the quantizer are equal to a positive or negative full-scale value. After overload is detected, the internal nodes within the Σ-Δ ADC are reset to their zero state and the attenuation setting is temporarily increased by 6 dB. The ADC reset is removed after 16 FADC clock cycles and over the next 48 FADC clock cycles, the attenuation is returned to its original value. If the input signal is such that an overload occurs again, this process repeats until the signal falls within the no overload range of the Σ-Δ ADC. Although the Σ-Δ ADC produces good data within 64 FADC clock cycles of the signal falling within the no overload range, the bad data associated with an overload event must be flushed out of the decimation filters before the output of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s completely clean of any memory effects.

[Figure 76 t](#page-26-0)o [Figure 79 s](#page-27-1)how the measured overload recovery response for each of the decimation filter modes (DEC\_MODE) when driven by a periodic pulsed CW waveform of 10 ns duration and 2% duty cycle. The narrow pulse region of the waveform was set to be only 1 dB higher than the other region with its peak power adjusted slightly above the overload threshold level resulting in an occasional overload event.

Each plot compares the envelope response between a pulse that results in an overload event to a pulse where the Σ-Δ ADC remains stable and includes a zoom in region showing settling time to within 1% following the large scale settling plot. Because the phase response recovers two to three samples before the envelope response, the phase response is not shown.

Note the following:

- The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) was configured for  $F_{IF} = 300$  MHz, BW = 100 MHz, and  $F_{ADC} = 3.2$  GHz.
- The absolute settling response for any decimation factor scales with f<sub>DATA\_IQ</sub>. For example, the settling time shown i[n Figure 77](#page-26-1) is an additional seven samples at  $f_{DATA\_IQ} = 200$  MSPS, thus the absolute settling time is 35 ns  $(7 \times 1/200 \text{ MSPS})$ .
- Selecting a decimation factor of 12 or 16 improves the absolute settling time because it reduces the additive delay caused by the last stage decimation filter.



<span id="page-26-0"></span>



<span id="page-26-1"></span>Figure 77. Comparison of Normalized IQ Magnitude Response for Decimate by 16 Case When a Pulsed CW Waveform (10 ns Width) Is Just Below and Above Peak Power Level, Resulting in ADC Overload



Figure 78. Comparison of Normalized IQ Magnitude Response for Decimate by 24 Case When a Pulsed CW Waveform (10 ns Width) Is Just Below and Above Peak Power Level, Resulting in ADC Overload



<span id="page-27-1"></span>Figure 79. Comparison of Normalized IQ Magnitude Response for Decimate by 32 Case When a Pulsed CW Waveform (10 ns Width) Is Just Below and Above Peak Power Level, Resulting in ADC Overload

### <span id="page-27-0"></span>**Σ-∆ ADC CONFIGURATION CONSIDERATIONS Maximum Input Power (PIN\_0dBFS and IDAC1**<sub>FS</sub>)

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) maximum full-scale input power (PIN\_0dBFS) for a sinusoidal input signal is dependent on the IDAC1 peak fullscale output current (IDAC1 $_{FS}$ ) and the  $R_{IN}$  of the attenuator (that is, 60  $\Omega$ ) as shown in the equation below.

$$
PIN\_0dBFS = 10 \times \log 10(1/2 \times R_{IN} \times IDAC1_{FS}^2)
$$
 (2)

The derivation of this equation becomes apparent when considering the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)nput stage consisting of RESON1, IDAC1, and  $R_{IN}$ , as shown i[n Figure 68.](#page-23-1)  $R_{IN}$  is the input resistance of the attenuator. The cascode transistor associated with IDAC1 and R<sub>IN</sub> establishes a low impedance node serving as a current mode summing junction whereby the input signal (equal to VIN±/R<sub>IN</sub>) is compared to the feedback signal from IDAC1. Note that the feedback loop of the  $\Sigma$ - $\Delta$  modulator attempts to generate an equal but opposite feedback current to cancel the signal current appearing at this summing junction.

Ultimately, the maximum feedback signal current that can be generated by IDAC1 is limited by its full-scale setting,  $IDAC1_{FS}$ , thus setting the 0 dBFS level on which feedback can no longer cancel any further increase in input signal level (or power). For example, the  $AD6676$  nominal setting for IDAC1 $_{FS}$  at 4 mA equates to a PIN\_0dBFS of −3 dBm, resulting in a differential voltage swing of ±240 mV peak.

Equation 2 assumes that the attenuator setting is 0 dB. Any setting beyond 0 dB increases the effective PIN\_0dBFS measured at the input of the attenuator by an amount equal to the attenuator setting.

In practice, the actual measured PIN\_0dBFS may vary a few tenths of a decibel for different application parameter settings due to some amount of pass band tilt. For this reason, PIN\_0dBFS is defined at the IF center.

### **LEXT Selection**

The range of permissible values for LEXT depends on the following application parameters:  $F_{IF}$ ,  $F_{ADC}$ , and IDAC1<sub>FS</sub>. [Figure 80 s](#page-27-2)hows the upper and lower settings ( $L_{MAX}$  and  $L_{MIN}$ ) when IDAC1 $_{FS}$  is set to its default settings of 4 mA. Note that the LMAX limit is set by the largest voltage swing across the LC tank and the L<sub>MIN</sub> limit is set by the maximum tuning capacitance available from an internal capacitor array.



<span id="page-27-2"></span>Figure 80. Maximum External Inductor Value as a Function of IF Frequency and Clock Rate for IDAC1 $_{FS}$  = 4 mA

Note the following points when selecting LEXT:

- Larger values of LEXT result in larger voltage swings across the LC tank. Selecting a value that is approximately 55% to 80% of the L<sub>MAX</sub> value can be considered with a lower value, typically resulting in improved IMD performance due to reduced voltage swing across the inductor. Conversely, a higher value may lead to a slight improvement in noise performance (mostly near the IF center), but at the expense of IMD performance.
- Inductor accuracy of 10% is sufficient because it falls well within the calibration range of the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) during its initialization phase on power-up.

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- Surface mount inductors can be either wire-wound or multilayer. The lower cost multilayer inductors typically have quality factors below 20 that may have a slight impact on th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) NSD performance. Compare performance between the two inductor types before making a decision to select a lower cost multilayer type.
- Because the voltage swing across the LC tank scales proportionally with IDAC1FS, which sets PIN\_0dBFS, a reduction in IDAC1FS allows an inversely proportional increase of  $L_{\text{EXT}}$  to maintain a similar voltage swing. Note that the minimum tuning capacitance from the internal capacitor array along with any parasitic PCB capacitance sets largest the L<sub>EXT</sub> as defined in Equation 3.

$$
L_{MAX\_TUNE} = ((2\pi \times F_{IF})^2 \times 7.1 \text{ pF})^{-1}
$$
 (3)

The minimum capacitance contribution of the array can be up to 6.6 pF due to ±20 process variation. An additional 0.5 pF of PCB parasitic capacitance is also included, thus a value of 7.1 pF is used.

Tie the two external inductors, LEXT, to the VDD2 supply via a 10 Ω resistor that includes a 0.1  $\mu$ F decoupling capacitor, as shown in [Figure 93.](#page-32-1) 

The following example highlights how LEXT can be determined with the following application parameters:  $F_{IF} = 150 \text{ MHz}$ ,  $F_{ADC} =$ 3.0 GHz and IDAC1 $_{FS}$  = 4 mA. Referring t[o Figure 80,](#page-27-2) the  $L_{MAX}$ and  $L_{MIN}$  range is from 20 nH to 70 nH. A value of 43 nH represents 61% of L<sub>MAX</sub> and thus is suitable. Note that if the IDAC1 $_{FS}$  is reduced to 2 mA, this value can be increased to 86 nH because this value is below the absolute maximum.

### **Reduced PIN\_0dBFS Operation via Scaling IDAC1FS**

The PIN\_0dBFS can be reduced by up to 12 dB because IDAC1<sub>FS</sub> is adjustable over a 4 mA to 1 mA span as defined by Equation 4.

$$
IDAC1_{FS} = 4 \text{ mA} \times (IDAC1\_FS/64) \tag{4}
$$

where IDAC1\_FS is the decimal equivalent of the value in Register 0x10A.

The  $L_{\text{EXT}}$  value can be increased proportionally to any reduction in IDAC $1_{FS}$  to maintain similar voltage swings across the LC tank.

The NSD and IMD performance are shown i[n Figure 81](#page-28-0) and [Figure 82 f](#page-28-1)or IDAC1<sub>FS</sub> settings of 4.0 mA, 2.0 mA, and 1.0 mA. [Figure 83 s](#page-28-2)hows the STF response for each of these cases. Note the following observations from this example:

- With an IF of 300 MHz, the absolute maximum inductor is 39 nH; therefore, this inductor value is selected for both  $IDAC1<sub>FS</sub> = 2.0 mA and 1.0 mA.$
- Reducing  $IDAC1_{FS}$  from 4.0 mA to 2.0 mA and doubling LEXT lowers the PIN\_0dBFS by 6 dB but increases the average in-band noise, IBN, by only 1.8 dB. The noise figure of the ADC therefore improves by 4.2 dB.
- Reducing IDAC1<sub>FS</sub> from 2.0 mA to 1.0 mA lowers the ADC full scale by a further 6 dB and increases the average inband noise by only 4.6 dB. In this case, the noise figure improvement is a modest 1.4 dB.
- The swept IMD performance shows a degradation at reduced IDAC1<sub>FS</sub> settings.
- The STF response remains largely unaffected by reduced IDAC1<sub>FS</sub> settings.



<span id="page-28-0"></span>Figure 81. NSD vs. IDAC1<sub>FS</sub> Setting with Decimate by 16, I/Q Output (IF = 300 MHz,  $BW = 100$  MHz,  $F_{ADC} = 3.2$  GHz)



<span id="page-28-1"></span>



<span id="page-28-2"></span>Figure 83. STF vs. IDAC1<sub>FS</sub> Setting with Decimate by 16, I/Q Output, Dual Tones Set to  $-8$  dBFS (IF = 300 MHz, BW = 100 MHz,  $F_{ADC} = 3.2$  GHz)

Some applications may benefit from a reduced IDAC1<sub>FS</sub> setting because a reduction in the PIN\_0dBFS levels results in a decibel per decibel reduction in the gain and linearity (P1dB, IIP3) requirements of the front-end driver. This enables a lower power RF line-up with the possibility of 3.3 V operations. Alternatively, it can allow a greater IF AGC operation range from the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) when the previous stages output (P1dB) level is set by its power supply setting. Carefully evaluate the tradeoff in the ac performance of th[e AD6676 w](http://www.analog.com/AD6676?doc=AD6676.pdf)hen deciding to operate at reduced IDAC1<sub>FS</sub> settings.

### **Using the MRGN Parameter to Optimize NTF**

The MRGN application parameters provide an additional degree of freedom when trying to optimize the NTF for a particular application. This feature is particularly useful when th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) operates with a low oversampling ratio where the quantization noise contribution begins to limit the NSD performance. In such cases, the default MRGN settings may not be adequate, resulting in regions of the pass band (typically at the edges) where the worst-case NSD is higher than in other regions. For these cases, the NTF can be optimized by adjusting the  $\Sigma$ - $\Delta$  ADC resonator frequencies in such a way that that result in a more optimally distributed NSD over the entire pass band.

The MRGN\_L, MRGN\_U, and MRGN\_IF parameters are located in Register 0x107 through Register 0x109. MRGN\_L and MRGN\_U specify the number of megahertz by which the lower and upper edges of the target pass band are extended, whereas MRGN\_IF specifies the resonance frequency offset of RESON1 from the center of the target pass band. The maximum setting in these registers must be in the range of 10 MHz to 20 MHz because higher offset settings can adversely affect the STF. The MRGN parameter is represented as an array equal to [MRGN\_L, MRGN\_U, MRGN\_IF].

The following example using a low oversampling ratio of 10 highlights the effects of the MRGN parameters on the NTF and STF. In this example, the goal is to optimize the worst-case NSD performance across a 160 MHz pass band region with  $F_{ADC}$  = 3.2 GHz and IF = 300 MHz while trying to preserve a flat STF. [Figure 84 s](#page-29-0)hows the corresponding NTF performance for different MRGN settings, an[d Table 8 l](#page-29-1)ists the resonant frequencies of RESON1, RESON3, and RESON3 that pertain to these settings. Note that the default setting of [5 5 0] results in the upper half of the pass band having the worst NSD (−141 dBFS/Hz at 380 MHz). Symmetrical MRGN settings of [10 10 0] and [15 15 0] are shown to highlight how the NTF varies as only the resonant frequencies of RESON2 and RESON3 are increasingly offset symmetrically about the IF center of 300 MHz. To improve on the default setting of [5 5 0], an asymmetrical setting of [8 16 2] that is weighted towards the upper half of the pass band region was found to achieve a more distributed worst-case NSD of −145 dBFS/Hz.



<span id="page-29-1"></span>**Table 8. Resonator Frequencies vs. MRGN Settings** 





<span id="page-29-0"></span>Maintaining a flat STF across the pass band is also desirable when modifying the MRGN settings[. Figure 84](#page-29-0) shows how each of the different MRGN settings affects the STF. Note that the asymmetrical MRGN setting of [8 16 2] results in an STF that is slightly skewed above IF center but still maintains ±0.5 dB flatness.





Whereas the previous example represents an extreme case, other cases having higher oversampling ratio can also potentially benefit from optimization. After the values of fcLK, IF, and BW have been determined for a particular application, it may be advantageous to explore whether a different MRGN setting yields any improvement. It is important to note that this sort of optimization is based on an iterative trial and error method. However, after the MRGN setting has been determined, both the STF and NTF remain repeatable.

## **Σ-∆ ADC Adaptive Shuffler**

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) includes a programmable adaptive shuffler that improves the SFDR and IMD performance of the Σ-Δ ADC under large signal conditions. As shown i[n Figure 68,](#page-23-1) the adaptive shuffler randomizes the selection of the unit elements used by the feedback DACs to reconstruct the output signal of the quantizer. Both static and dynamic mismatch errors associated with the quantizer and feedback DACs are dithered such that the spurious contribution is spread across a wider frequency span. [Figure 86 c](#page-30-0)ompares the improved IMD performance for a two tone excitation when the shuffler is enabled and disabled.



<span id="page-30-0"></span>Figure 86. IMD Performance when Shuffler Is Disabled vs. Enabled for Two CW Tones at  $-8$  dBFS, (F<sub>IF</sub> = 180 MHz, BW = 80 MHz, F<sub>ADC</sub> = 3.2 GHz, L<sub>EXT</sub> = 43 nH)

Although the shuffler improves the SFDR and IMD performance, it does so at the expense of the in-band NSD performance. For this reason, both the degree of shuffling as well as the enabling threshold relative to the quantizer output code is user programmable, allowing optimization for a target application. The shuffling rate is variable from 1 to 4 ADC clock cycles ( $1/F<sub>ADC</sub>$ ). The shuffler remains enabled for a fixed amount of clock cycles from the instant that the input signal falls below this threshold and remains below it.

The enabling threshold is relative to the quantizer code and represents the peak absolute value that triggers the shuffler. The quantizer can produce an output code ranging from −8 to +8, therefore the threshold can assume a value between 0 to 8. The 4-bit value is set via Register 0x342 or Register 0x343. A hexadecimal value of 0x0 sets the shuffler to always enabled whereas a value of 0xF effectively disables the shuffler.

The 4-bit fields in Register 0x342 and Register 0x343 set the threshold value based on the shuffling rate selected. Set only the 4-bit field pertaining to the selected shuffling rate while the remaining nonapplicable 4-bit fields set to 0xF. Disable the shuffler by setting all the 4-bit fields to 0xF, the highest threshold setting. [Table 9](#page-30-1) shows the SPI register settings for the various shuffling modes when the threshold is set to its default setting of 5. Other threshold values ranging from 3 to 8 are also possible. [Table 10](#page-30-2)  shows the input power level that triggers the shuffler for different threshold value settings when driven by a continuous wave tone.

<span id="page-30-1"></span>

Table 9. Default SPI Register Settings for Adaptive Shuffling							
<b>Shuffling Rate</b>	<b>Register 0x342</b>	<b>Register 0x343</b>					
FADC	0xF5	0xFF					
$F_{ADC}/2$	0x5F	0xFF					
$F_{ADC}/3$	0xFF	0xF5					
$F_{ADC}/4$	0xFF	0x5F					
Disable shuffler	0xFF	0xFF					

<span id="page-30-2"></span>**Table 10. Threshold Setting Values that Trigger the Shuffler for a Continuous Wave Tone** 



When enabled, the shuffler can introduce colored noise into the pass band spectrum. This additional noise is a result of the increased switching activity within the  $\Sigma$ - $\Delta$  ADC core along with the pseudorandom element selection process, thus resulting in signal level dependent colored noise at frequency offsets related to the shuffling rate[. Figure 87 h](#page-31-0)ighlights the effect of the colored noise between shuffle every four clock cycles vs. one cycle with and without a large signal continuous wave tone present and the shuffling threshold set to 0.

Typically, the shuffling threshold is set in the range of 4 to 6. This example serves to highlight the colored noise effects of shuffling. Selecting a higher threshold setting is preferable when trying to preserve the NSD performance. For this reason, the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) default threshold setting is 5 with the shuffle every clock cycle option.

The four-cycle option introduces visible noise humps with a −1 dBFS signal level. This colored noise is at an offset of  $f_{CLK}/128$ , resulting from the pseudorandom element selection process. Other shuffling options also introduce colored noise but at a greater frequency offset that are related to the shuffling rate factor (SRF) as described by the following equation:

$$
Frequency \; Offset = f_{CLK}/(32 \times SRF) \tag{5}
$$

The effect of this colored noise is worthy of consideration when selecting the shuffling rate and threshold. For example, sweeping a −1 dBFS continuous wave tone across the usable IF pass band region while monitoring the NSD characteristics is helpful to identify what shuffling rate may have the least impact on the NSD performance.



<span id="page-31-0"></span>Figure 87. NSD Performance of the Various Shuffling Settings with No Signal; Threshold Set to 0 (Shuffler Is Always Enabled);  $F_{IF} = 180$  MHz, BW = 80 MHz,  $F_{ADC} = 3.2$  GHz,  $L_{EXT} = 43$  nH



Figure 88. NSD Performance of the Various Shuffling Settings with a −1 dBFS Signal; Threshold Set to 0 (Shuffler Is Always Enabled);  $F_{IF} = 180$  MHz, BW = 80 MHz,  $F_{ADC} = 3.2$  GHz,  $L_{EXT} = 43$  nH

The degradation in NSD performance is also dependent on the input signals amplitude; thus, it is important to select a shuffling rate and threshold setting that result in an optimum trade-off between large signal linearity performance and low signal level in-band noise performance[. Figure 89](#page-31-1) shows how the in-band noise (dBFS) degrades at increasing signal levels for the same settings used in [Figure 87.](#page-31-0) In this example, a continuous wave tone is placed just above the pass band with its power swept from −40 dBFS to −1 dBFS. At low signal levels (less than −20 dBFS), the degradation in in-band noise performance is dependent on the shuffling rate. At higher signal levels (greater than−20 dBFS), the degradation is a result of increased colored noise falling in the pass band. Selecting a shuffle rate of every two ADC cycles with a threshold in the range of 4 or 5 is a good compromise, as shown i[n Figure 90.](#page-31-2)



<span id="page-31-1"></span>Figure 89. Pass Band Degradation in IBN (dBFS) as a Continuous Wave Tone at 225 MHz, Swept from −40 dBFS to −1 dBFS with Different Shuffling Rate Settings, Threshold Set to 0,  $F_{IF} = 180$  MHz, BW = 80 MHz.  $F_{ADC} = 3.2$  GHz,  $L_{EXT} = 43$  nH



<span id="page-31-2"></span>Figure 90. IBN vs. Input Power Performance for Threshold Settings of 4 and 5 When Configured for Shuffle Every Two ADC Cycles

After a particular shuffling configuration is selected, the effects on the Σ-Δ ADC performance remain repeatable over time and among different devices

### **Σ-∆ ADC Profile Feature**

The [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)ncludes a feature that allows the  $\Sigma$ - $\Delta$  ADC to store up to four different profile settings that can be recalled quickly via Register 0x118 without recalibrating the Σ-Δ ADC. Calibration of each of the different profiles specified in Register 0x115 occurs during the device initialization phase with each profile consisting of the following various application parameters: BW, F<sub>IF</sub>, IDAC1<sub>FS</sub>, and MRGN. FADC, along with the decimation filter and JESD204B settings, remains common to ensure that the JESD204B link is maintained when switching between profile settings. Note that the  $\Sigma$ - $\Delta$  ADC is operational with the updated profile settings within 1 µs upon receipt of the SPI command.

# Data Sheet **AD6676**

The following example highlights how this feature is used for applications that require wide bandwidth capability but not necessarily instantaneous bandwidth. In these applications, it may be possible to divide the required IF bandwidth into narrow subbands where the Σ-Δ ADC can provide higher dynamic range. For instance, in an application that requires 120 MHz of IF bandwidth, consider dividing this bandwidth into three contiguous blocks of 40 MHz, with each IF being offset by 40 MHz[. Figure 91](#page-32-2) shows that the worst-case NSD is limited to −149 dBFS/Hz when th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) is configured for the wider bandwidth of 120 MHz[. Figure 92](#page-32-3) shows how the NSD performance is improved by 10 dB when the 120 MHz bandwidth is subdivided into three 40 MHz bands.



<span id="page-32-2"></span>Figure 91. NSD Performance with Wideband Profile ( $F_F = 260$  MHz, BW = 120 MHz,  $F_{ADC} = 3.2$  GHz,  $L_{EXT} = 27$  nH)



<span id="page-32-3"></span>Figure 92. NSD Performance with Narrow-Band Profiles ( $F_{IF} = 220$  MHz, 260 MHz, and 300 MHz, BW = 120 MHz,  $F_{ADC} = 3.2$  GHz,  $L_{EXT} = 27$  nH)

In this example, the frequency and phase settings of the digital mixer remained common among the various profiles such that it remained centered upon 260 MHz. It is also possible to provide a unique digital mixer setting for each profile if it is desirable to re-center the digital IF frequency. This feature is desirable in instances where the range of IFs cannot be supported by the pass band response of the digital decimation filter.

## <span id="page-32-0"></span>**ATTENUATOR**

Th[e AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)ncludes an on-chip differential 27 dB attenuator with a resolution of 1 dB. The attenuator can be used to rescale the fullscale input level into the ADC for system calibration or for optimization purposes or to prevent possible overload of the Σ-Δ ADC when used with external AGC control[. Figure 93 s](#page-32-1)hows a simplified equivalent circuit of the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) input stage, which includes RESON1 and IDAC1. The attenuator provides a nominal input resistance (R<sub>IN</sub>) of 60 Ω to the signal source to facilitate its interface to external driver circuitry. The attenuator is configurable via Register 0x181 to Register 0x183 and includes options for fast external gain control via the AGC pins. Note that the latency from when an external CMOS signal is applied to the AGC pins to when the attenuator changes state is within 5 ns.



Figure 93. Simplified Equivalent Input

<span id="page-32-1"></span>Attenuation is achieved by a programmable shunt and series resistor network that steers some designated amount of input current away from the summing junction while keeping the nominal input resistance near 60  $Ω$  over the full attenuation span. For a 0 dB setting, no shunt resistance exists; therefore, all of the input current is fed into the summing junction. For a 6 dB setting, the attenuator is configured with a 120  $\Omega$  shunt resistor operating in parallel with two 60  $\Omega$  series resistors such that half of the signal input current is directed into the summing junction while maintaining a nominal 60 Ω input resistance. Other settings function in a similar manner with resistor values modified to achieve the desired attenuation value while maintaining the nominal R<sub>IN</sub>. [Figure 94 s](#page-33-0)hows the differential S11 of th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) input for different attenuator settings.



<span id="page-33-0"></span>Figure 94. Differential S11 vs. Frequency for Different Attenuator Settings

The accuracy of the attenuator is an important consideration in applications implementing AGC or system calibration. The attenuator remains monotonic over its full operating range. [Figure 95,](#page-33-1) which shows a typical devices attenuation error vs. attenuation state at −40°C, +25°C, and +85°C, demonstrates the near instrumentation level accuracy of th[e AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)ttenuator.



<span id="page-33-1"></span>Figure 95. Typical Attenuation Step Size Error vs. Setting over Temperature

The linearity performance of the attenuator is another consideration when determining the largest input drive levels before its nonlinearity may dominate over that of the Σ-Δ ADC. The effective PIN\_0dFS level of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s increased decibelper-decibel by the attenuator setting. At large attenuator settings, the peak-to-peak voltage swing seen at the VIN+ and VIN− pins increases as well as the current that is steered into the attenuator shunt resistance. At a certain level, the IMD contribution from the attenuator begins to dominate over the  $\Sigma$ - $\Delta$  ADC contribution. [Figure 96 p](#page-33-2)lots the worst third-order IMD spurious vs. attenuator setting for IDAC1Fs of 4 mA and 2 mA with the power of the dual tones increased to maintain a constant −8 dBFS level measured by the  $\Sigma$ - $\Delta$  ADC. The effective PIN\_0dBFS is also plotted to show the maximum continuous wave signal level into the device that results in a 0 dBFS level.

Note the following conditions and observations:

- The  $AD6676$  is configured as follows: IF = 180 MHz, BW = 80 MHz, and  $f_{CLK} = 3.2$  GHz. Tones are situated at 177.5 MHz and 182.5 MHz.
- The PIN\_0dBFS level is reduced by 6 dB when  $\rm IDAC1_{FS}$  is reduced to 2 mA.
- The IMD performance remains below −80 dBc until an attenuator setting of 9 dB.
- Further increases in the two-tone power lead to a corresponding steady decline in the IMD performance due to the nonlinearity of the attenuator.
- Although not shown, the NSD performance centered about the IF improves a few dB with increased attenuation.



<span id="page-33-2"></span>Figure 96. IMD Component Degradation as Two-Tone Centered at an IF of 180 MHz Is Increased 1 dB for Every 1 dB Increase in Attenuator Setting, Such That Two-Tone Level Remains at −8 dBFS

The effects of switching transients are another important consideration for AGC implementations that digitally calibrate gain changes in the signal path of the receiver that can otherwise degrade the demodulation of the desired signals.

[Figure 97 a](#page-34-1)nd [Figure 98 s](#page-34-2)how the IQ envelope response when the attenuator state is switched between 0 dB and 6 dB via an external control signal using the AGC2 input pin at a rate of 3.3 MHz. Note that the settling response is dominated by the response of the digital filter (decimate by 12) and shows no signs of glitch.



<span id="page-34-1"></span>Figure 97. Wide Envelope Response for 6 dB Attenuator Step Change with  $f_{DATA_1Q} = 250$  MSPS, Resulting Sample Period of 4 ns



<span id="page-34-2"></span>Figure 98. Zoom In Envelope Response for 6 dB Attenuator Step Change with  $f_{DATAIO} = 250$  MSPS, Resulting Sample Period of 4 ns

## <span id="page-34-0"></span>**CLOCK SYNTHESIZER**

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) includes an on-chip clock synthesizer capable of generating the clock for the  $\Sigma$ - $\Delta$  ADC and digital circuitry. The entire synthesizer is integrated on-chip, including the loop filter and VCO. [Figure 99 s](#page-34-3)hows a functional block diagram of the various synthesizer subblocks along with the relevant SPI registers. The clock synthesizer uses a standard integer-N architecture to generate a 2.94 GHz to 3.2 GHz ADC clock from a 10 MHz to 320 MHz reference input.

Configuring the clock synthesizer requires numerous SPI commands to program settings and to initiate calibrations. The SPI sequence to configure th[e AD6676 f](http://www.analog.com/AD6676?doc=AD6676.pdf)or a particular operating mode, including the SPI operations associated with the clock synthesizer, is most easily obtained from the software tool that comes with the [AD6676EBZ d](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)evelopment platform. This tool allows the SPI sequence used to configure th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) to be saved to a file for later use.

Note that if the clock synthesizer is used to supply the ADC clock, the clock synthesizer must be configured first, before any other blocks are enabled. Also note that because the clock synthesizer sequence involves calibrations, wait intervals or polling loops are needed to ensure that each calibration step completes before issuing the next SPI command[. Table 27](#page-62-0) lists an example SPI sequence for a particular case where the reference frequency ( $f_{\text{CLK}}$ ) and ADC clock rate ( $F_{ADC}$ ) are 200 MHz and  $F_{ADC} = 3200$  MHz, respectively. The remainder of this section describes the configuration of the clock synthesizer in detail.

<span id="page-34-3"></span>

Figure 99. CLK Synthesizer Block Diagram

### **R and N Dividers**

The phase/frequency detector (PFD) requires a 10 MHz to 80 MHz clock. When  $f_{CLK} = 200 \text{ MHz}$ , the R divider must be set to divide by 4 so that  $f_{\text{PFD}} = f_{\text{CLK}}/R_{\text{DIV}} = 50 \text{ MHz}$ , which is within the supported range[. Table 11](#page-35-0) shows the mapping from RDIV to the value of Register 0x2BB. This register is set in Step 6 o[f Table 27.](#page-62-0) 

### <span id="page-35-0"></span>**Table 11. R Divider Settings for Register 0x2BB**



Note that operating with the highest permissible fPFD minimizes the clock synthesizer reference spur because the PLL filter bandwidth is fixed at 200 kHz. For a sinusoidal clock input signal that has a limited input slew rate, operation with an input frequency that is  $2 \times$  or  $4 \times$  the desired f<sub>PFD</sub> can also result in a slight improvement in phase noise performance.

Because the ADC clock is obtained by dividing the VCO clock by 2, the N-divider must be set according to

 $N = 2F_{ADC}/f_{PFD} = 2 \times 3.2$  GHz/50 MHz = 128 = 0x80

The value of N is programmed by writing the LSB (0x80) to Register 0x2A1 and the MSB (0x00) to Register 0x2A2 and is set in Step 1 o[f Table 27.](#page-62-0)

### **Charge Pump Current and Calibration**

The charge pump current setting (Register 0x2AC) is given by

$$
I_{CP} = round(min(63, \frac{1.33 \times 10^{28}}{f_{PFD} \times F_{ADC}^2} - 1))
$$
 (6)

For the  $F_{ADC}$  and  $f_{\text{PFD}}$  values used in this example, ICP evaluates to 25, or 0x19; this value is programmed in Step 4 o[f Table 27.](#page-62-0)

The charge pump also must be calibrated during the clock synthesizer initialization phase. Calibration is triggered via Register 0x2AD The time required to complete the calibration is inversely proportional to the PFD frequency. For example, using  $f_{\text{PFD}} = 10 \text{ MHz}$  requires a maximum 4 ms wait period but increasing f<sub>PFD</sub> to 80 MHz decreases the maximum wait period by a factor of 8 to 0.5 ms. Alternatively, poll Bit 0 of Register 0x2BC; charge pump calibration is complete when this bit is set.

### **VCO Configuration and Calibration**

VCO configuration consists of writing to the SPI registers in [Table 12 t](#page-35-1)hat control the VCO core bias, temperature compensation, and varactor settings. These settings depend on the VCO frequency and are optimized via characterization to ensure proper operation of the PLL over supply and temperature.

<span id="page-35-1"></span>



<sup>1.</sup> Operation at 3200 MHz requires the following modification to the KVCO and charge pump resistor settings: Register  $0x2A9 = 0x2A$  and Register  $0x2AC =$ 0x12.

The VCO also must be calibrated during the clock synthesizer initialization phase to ensure proper operation over its full temperature range. VCO calibration is triggered via Register 0x2AB with the amount of time required to complete the calibration again being inversely proportional to the PFD frequency. Specifically,  $f_{\text{PPD}} = 10 \text{ MHz}$  requires a 2 ms wait period whereas  $f_{\text{PFD}} = 80 \text{ MHz decreases}$  the wait period by a factor of 8 to 0.25 ms. Alternatively, poll Bit 1 of Register 0x2BC; VCO calibration is complete when this bit is clear.

After the initialization process is complete, verify that Bit 3 of Register 0x2BC is set to confirm that the PLL is locked.
# **Phase Noise Performance**

Above the PLL filter bandwidth of 200 kHz, the internal VCO limits the overall phase noise of the clock synthesizer. The VCO phase noise performance shows a slight improvement at its low end of its FADC operating range, as shown i[n Figure 100 T](#page-36-0)he phase noise for a particular IF input frequency can be calculated using Equation 5.

$$
PN_{fIN\_OFFSET} = PN_{fCLK\_OFFSET} + 20 \times \log (F_{IF}/F_{ADC})
$$
 (7)

For example, the phase noise at 1 MHz offset for an FADC of 3.2 GHz is approximately −124 dBc/Hz. An IF input frequency of 200 MHz results in a 24 dB improvement, thus the expected phase noise at 1 MHz offset is −148 dBc/Hz.



<span id="page-36-0"></span>Figure 100. Clock Synthesizers Typical Phase Noise for Various FADC Values

The repeatability of a device that is power cycled 10 times is shown i[n Figure 101.](#page-36-1) Note that the measured data in this figure aligns with the expected results based on Equation 5 an[d Figure 100.](#page-36-0) The phase noise variation over temperature of a nominal device is shown in [Figure 102.](#page-36-2)



<span id="page-36-1"></span>Figure 101. Power Cycle Repeatability (10 Attempts) of Phase Noise Measurement for an IF Input Frequency of 225 MHz and  $f_{CLK} = 2.94912$  GHz with PLL PFD  $= 61.44$  MHz



<span id="page-36-2"></span>Figure 102. Typical Temperature Stability of Clock Synthesizer with the Same Conditions a[s Figure 101](#page-36-1)

# DIGITAL PROCESSING BLOCKS

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) includes the following digital blocks between the Σ-Δ ADC output and JESD204B transmitter core:

- An ADC overload and recovery block immediately follows the ADC. This circuitry quickly detects any ADC instability from an overload event while ensuring fast recovery.
- A digital signal processing block translates the real IF signal from the Σ-Δ ADC to a complex zero IF, suitable for postprocessing by the host without loss of any dynamic range. This block includes both coarse and fine QDDCs, along with a selectable FIR decimation filter stage that provides decimation factors of 12, 16, 24, and 32.
- A peak detection and AGC support block facilitates the implementation of an external AGC control loop under the control of the host. Note that the AGC pins can also be repurposed for GPIO functions.

[Figure 103](#page-37-0) shows a diagram of the digital functional blocks along with the SPI configurable registers pertaining to these blocks. The following sections provide more insight into the operation of each of these functional blocks. More information pertaining to these SPI registers can be found i[n Table 32 t](#page-65-0)hrough [Table 135.](#page-88-0) 



<span id="page-37-0"></span>Figure 103. Simplified Block Diagram of Digital Processing Blocks

# **DIGITAL SIGNAL PROCESSING PATH**

The Σ-Δ ADC provides a highly oversampled 5-bit digital output representing the desired IF signal pass band as well as the out-of-band shaped noise described earlier. Referring t[o Figure 104,](#page-38-0)  the digital signal processing path translates this oversampled real IF signal to a complex dc centered IF signal, having a more manageable data rate suitable for transfer via the JESD204B interface. The QDDC performs the real-to-complex frequency translation followed by digital filtering to remove the ADC out-of-band noise, as well as any other undesired signal content, before decimation to a lower data rate without any loss of dynamic range.



<span id="page-38-0"></span>Figure 104. Digital Signal Processing Path Performs Frequency Translation to a Zero IF as well as Filtering and Downsampling

# **Quadrature Digital Downconversion**

Digital downconversion occurs in two stages using a coarse and a fine QDDC. As shown in [Figure 103,](#page-37-0) the coarse QDDC resides immediately after the Σ-Δ ADC and the fine QDDC follows the first decimation stage. The coarse QDDC provides 6-bit tuning resolution whereas the fine QDDC provides 10-bit tuning resolution. The composite tuning resolution is either F<sub>ADC</sub>/3072 or F<sub>ADC</sub>/4096, depending on whether the first decimation stage is configured for 3× or 4× decimation, which in turn depends on the decimation mode selected as described in [Table 13.](#page-38-1) For applications requiring finer tuning resolution to position the IF signal exactly about dc, consider adding a finer resolution QDDC in the host processor.

<span id="page-38-1"></span>



The tuning frequency settings of the combined coarse and fine NCO (SPI Register 0x141 and SPI Register 0x142) are automatically calculated and set by the [AD6676 d](http://www.analog.com/AD6676?doc=AD6676.pdf)uring the device SPI initialization phase. The user defined FADC and IF settings (SPI Register 0x100 thru SPI Register 0x103) are used to calculate the settings such that the center of the IF pass band is centered about dc. The coarse tuning NCO is set via MIX1\_TUNING[5:0], whereas the fine tuning NCO is set via MIX2\_TUNING[7:0]. The decimal equivalent frequency setting of each NCO register is based on the following equations.

$$
MIXI = \text{Round}\left(64 \times \frac{F_{IF}}{F_{ADC}}\right) \tag{8}
$$

where:

MIX1 is a 6-bit binary number representing the NCO frequency setting in MIX1\_TUNING.

 $F_{IF}$  is the desired carrier frequency in hertz (Hz). FADC is the ADC clock rate in hertz (Hz).

$$
MIX2 = \text{Round}\left(M \times \left(\frac{F_{IF}}{F_{ADC}} - \frac{MIX1}{64}\right)\right) \tag{9}
$$

where:

MIX2 is a 8-bit twos complement number representing the NCO frequency setting in MIX2\_TUNING.  $M$  is 3072 for DEC\_MODE = 2 and 4, or 4096 for DEC\_MODE = 1 and 3.

It is important to note the residue, for FSET, between the desired  $F_{IF}$  and th[e AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)omposite NCO setting,  $F_{IF\_NCO}$ , because any offset may need to be compensated with an additional fine QDDC located in the host processor. Use the following equations to calculate both parameters:

$$
F_{IF\_NCO} = \left(\frac{MIX1}{64} + \frac{MIX2}{M}\right) \times F_{ADC}
$$
 (10)

$$
f_{\text{OFFSET}} = F_{\text{IF}} - F_{\text{IF\_NCO}} \tag{11}
$$

# **Example**

Calculate the NCO MIX1 and MIX2 values along with  $F_{IF\_NCO}$ and f<sub>OFFSET</sub> with the followin[g AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)onfiguration:  $F_{IF}$  = 140 MHz, FADC = 3200 MHz, and decimation factor of 16 (that is,  $f<sub>DATA IO</sub> = 200 MSPS$ .

- Substituting  $F_{IF}$  and  $F_{ADC}$  values in Equation 8 results in  $MIX1 = 3.$
- Substituting these values in Equation 9 (noting that  $M =$ 4096 for DEC\_MODE = 3 results in MIX2 =  $-13$ ).
- Substituting MIX1 and MIX2 values into Equation 10 results in  $F_{IF\_NCO} = 139.84375 \text{ MHz}.$
- Substituting  $F_{IF}$  and  $F_{IF\_NCO}$  values in Equation 11 results in  $f_{OFFSET} = 156.25$  kHz.

# **NCO Phase Synchronization**

The [AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)oarse and fine tuning NCOs can be set to an initial phase after synchronization with an external SYSREF signal. The initial phase of the coarse tuning NCO is set via MIX1\_INIT, with an LSB corresponding to 1/64<sup>th</sup> of a cycle. The initial phase of the fine tuning NCO is set via MIX2\_INIT\_x, with an LSB corresponding to  $1/1024^{\text{th}}$  of a cycle.

# **Digital Filter Modes**

The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) digital filter path is designed to provide sufficient stop band rejection of the Σ-Δ ADC shaped out-of-band noise as well as any spurious noise that otherwise might alias back into the desired pass band region after decimation and limit the actual NSD performance. The filter path supports decimation factors of 12, 16, 24, and 32 depending on the DEC\_MODE setting. The complex output of the coarse QDDC feeds a pair of symmetrical FIR decimation filters divided into three stages, as shown in [Figure 103.](#page-37-0) The first stage is a decimate by 3 or by 4 filter, depending on whether the desired decimation factor is divisible by three. The second and third stages consists of two cascaded decimate by 2 filters with the third stage outputs supporting the decimate by 12 and by 16 options. A bypassable fourth stage provides the decimate by 24 and by 32 options.

The normalized pass band and wideband folded frequency response for each filter mode are shown in [Figure 105](#page-40-0) through [Figure 113.](#page-41-0) Note the following observations:

- All filter responses provide a linear phase response over its pass band.
- The usable IF bandwidth depends on the DEC\_MODE as well as the minimum acceptable pass band ripple and stop band rejection requirements[. Table 14](#page-39-0) provides the normalized usable complex bandwidth vs. DEC\_MODE for stop band rejections of greater than 85 dB and 60 dB.
- The last filter stage sets the usable bandwidth and stop band rejection because it has the most aggressive transition band specifications. For this reason, the decimation factors of 12 and 16 have the same normalized usable bandwidths as does decimation factors of 24 and 32.
- Wide IF bandwidths (MHz) are supported when operating at lower decimation factors along with a high  $F_{ADC}$ .
- It is worth noting that many applications requiring wider IF bandwidth may tolerate reduced ripple and rejection as the digital filter response enters its transition region. The reason is that the Σ-Δ ADC achievable NSD performance at the IF pass band edges also degrades as its oversampling ratio is reduced, thus still dominating relative to any aliased noise due to reduced filter stop band rejection.



# <span id="page-39-0"></span>**Table 14. Usable Normalized Complex Bandwidth vs. Decimation Factor**

# **Total Pipeline Latency**

The digital filter path dominates the latency of th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) whereas the JESD204B PHY adds a few samples of delay and the ADC delay is a fraction of an output sample. The latency between the ADC and digital filter output is fixed with the only nondeterministic delay being associated with the JESD204B PHY clock and lane FIFOs before synchronization. See the [Synchronization Using SYSREF s](#page-50-0)ection for additional information[. Table 15 p](#page-39-1)rovides the nominal pipeline delay associated with each DEC\_MODE. Note that although all DEC\_MODE settings provide similar delays relative to the output data rate,  $f<sub>DATA_IQ</sub>$ , applications that require shorter absolute time delays may consider using a lower decimation factor to reduce the absolute delay by 2×.

<span id="page-39-1"></span>





Figure 105. Pass Band Frequency Response of Decimate by 12

<span id="page-40-0"></span>

Figure 106. Pass Band Frequency Response of Decimate by 16



Figure 107. Pass Band Frequency Response of Decimate by 24



Figure 108. Folded Frequency Response of Decimate by 12 Shows Alias Rejection



Figure 109. Folded Frequency Response of Decimate by 16 Shows Alias Rejection



Figure 110. Folded Frequency Response of Decimate by 24 Shows Alias Rejection



# **AGC FEATURES AND PEAK DETECTION**

In receiver applications, it is desirable to have a mechanism to reliably determine when the converter is about to be overdriven. The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) Σ- $\triangle$  ADC is based on a feedback loop that can be overdriven into a nonlinear region, resulting in oscillation. This oscillation persists until the Σ-Δ ADC is reset and the overload condition is removed. Typically, a receiver lineup employs some form of AGC that attempts to avoid this scenario.

The [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)ipeline latency along with any additional overhead associated with the host processor (JESD204B Rx PHY) may limit the ability to design a fast reacting digital-based AGC required by some applications. For this reason, the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)ncludes the AGCx pins that serve as digital input/ outputs to facilitate the implementation of a fast AGC control loop under the control of the host. The AGC4 and AGC3 pins can be allocated to provide flag outputs after a programmable threshold has been exceeded, including an ADC reset event, while the AGC2 and AGC1 pins can be used to control the onchip attenuator. Register 0x18F and Register 0x193 through Register 0x19E are used for AGC purposes.

# **Peak Detection and AGC Flags**

Peak detection occurs at the output of the second stage decimation filter, as shown i[n Figure 103.](#page-37-0) Detection at this stage represents a compromise between the accuracy of the peak detector, delay time and ability to measure large out-of-band signals. At this stage, the Σ-Δ ADC output signal has been frequency translated to dc and its out-of-band noise sufficiently filtered for reasonable threshold detection accuracy down to −12 dBFS peak signal levels. Note that the peak detector monitors the peak power envelope response of the IF input signal and calculates the peak power (that is,  $I^2 + Q^2$ ) expressed in dBFS with 12-bit resolution.

Because the peak detector is monitoring the peak power at the output of the second stage decimation filter, it provides a wider frequency range than what can be observed in the final IQ data output. The first stage filter is decimate by 3 or by 4; therefore, the output of the second stage filter can be  $1/6^{th}$  or  $1/8^{th}$  of  $F_{ADC}$ . [Figure 113](#page-41-0) shows the normalized measurement bandwidth relative to the output rate of the second stage filter centered about its zero IF[. Table 16 r](#page-41-1)eferences the measurement bandwidth to  $f_{\text{DATA}$  IQ for the different decimation factors such that its absolute bandwidth can be easily determined. For example, the −1 dB bandwidth for an fDATA\_IQ of 100 MSPS with decimate by 24 or by 32 is 200 MHz and remains at 200 MHz if the decimation factor is reduced to decimate by 12 or by 16. Any droop occurring at the pass band edges, as well as the Σ-Δ ADC STF, must be considered when setting thresholds.



<span id="page-41-0"></span>Figure 113. Normalized Pass Band Filter Response Seen by the Peak Detector

<span id="page-41-1"></span>



flag to prevent overloading the  $\Sigma$ - $\Delta$  ADC.

Note that the EN\_FLAGx bits provide the additional option of logically OR'ing an ADC reset event with an upper peak threshold event to provide an even faster output flag to the host processor indicating that the attenuation must be applied. This scenario applies to the extreme case where the envelope response of a blocker is exceedingly fast, such that the AGC cannot react fast enough to the upper peak threshold setting

> [Figure 114](#page-43-0) provides an example of how the Flag 0 and Flag 1 assigned pins behave to the envelope response of an arbitrary IF input signal. Flag 1 is assigned an upper threshold set by PKTHRH1\_x, and Flag 0 is assigned a lower threshold and dwell time set by LOWTHRH\_x and DWELL\_TIME\_x. The Flag 1 indicator goes high when the PKTTHR1\_x threshold is exceeded and returns low when the signal envelope falls below this threshold. The Flag 0 indicator goes high only when the envelope of the signal remains below the LOWTHRH\_x threshold for the designated dwell time. If the signal level exceeds the LOWTHRH\_x threshold before the dwell time counter has expired, the dwell time counter resets again and the Flag 0 indicator remains low until the conditions has been met.

> By offsetting the PKTTHR1\_x and LOWTHRH\_x threshold settings as well as optimizing the dwell time setting, it may be possible to optimize the operation of an AGC so that it reacts to signal strength variation due to fading conditions as opposed to the peak to minimum response associated with digital modulated signals.

# **IF Attenuator Control via the AGC2 and AGC1 Pins**

Many AGC implementations require fast gain control if the AGC threshold is exceeded. Th[e AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)rovides two modes in which the IF attenuator can be quickly changed via the AGCx pins. Use Register 0x180, Bit 0, to select the mode. The first mode uses the AGC2 pin to switch between two attenuator settings that are user defined in Register 0x181 and Register 0x182. The second mode uses the AGC2 and AGC1 pins to decrement and increment respectively the attenuation value in 1 dB steps with pulsed inputs. The starting attenuator value is defined in Register 0x183. The actual attenuator value can be read back via Register 0x184.

The first mode is used for the default [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)ower-up setting with both Register 0x181 and Register 0x182 set to 0x0C. For applications that do not require IF attenuator control but require a different attenuator setting, update both registers with the desired attenuator setting value such that the attenuator remains independent of the AGC2 pin state, if it is left floating. Note that connecting the unused AGC2 and AGC1 pins to VSSD via 100 k $\Omega$  pull-down resistors is still the preferred method if these pins are unused.

The [AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)llows the user to set three threshold settings that can trigger one of two possible flags. PKTHRH0 and PKTHRH1 are two upper threshold settings while LOWTHRH is a lower threshold setting. The threshold settings are 12 bits with an MSB and LSB register assigned to each threshold. The 12-bit decimal equivalent value can be calculated using Equation 12.

Threshold =  $3584 + (Threshold Setting in dBFS) \times 256/3$  (12)

where 0 dBFS corresponds to 3584 (0xE00) and −6 dBFS corresponds to 3072 (0xC00).

In the time domain, a 0 dBFS setting corresponds to a signal whose peaks observed at the I and Q outputs can reach plus or minus full scale. Meaning, if the 16-bit I and Q output data are normalized such that its peak values correspond to  $\pm 1$ , a 0 dBFS setting corresponds to a signal whose peak can reach the unit circle of a normalized I/Q constellation diagram.

The LOWTHRH\_x register has an associated dwell time of which the signal must remain below this threshold before a flag can be set. The dwell time is represented in exponential form to realize long dwell periods because the counter operates at F<sub>ADC</sub>/12 for decimate by 12 or 24 settings or F<sub>ADC</sub>/16 for decimate by 16 or 32 settings. The dwell time is set in the DWELL\_TIME\_ MANTISSA register and DWELL\_TIME\_EXP register using Equation 13 relative to 1/FADC.

Dwell Time =  $N \times$  [DWELL\_TIME\_MANTISSA]  $\times$  $2^{(DWELL\_TIME\_EXP)}$ (13)

where:

 $N = 12$  for decimate by 12 or 24.

 $N = 16$  for decimate by 16 or 32.

A flag function can be assigned using the FLAG0\_SEL register and FLAG1\_SEL register to indicate when any of the thresholds have been exceeded or if an ADC reset event has occurred. These flags must also be enabled via the EN\_FLAG register such that a CMOS level signal appears on the AGC4 and AGC3 pins where a logic high indicates when a threshold has been exceeded.

The delay relative to the ADC input when an AGC threshold is exceeded to when the flag signal goes high is dependent on the DEC\_MODE setting selected. For a DEC\_MODE value of 1 or 2 (decimate by 32 or 24), the delay equates to 8 to 9 output samples ( $1/f_{DATA_IQ}$ ). For DEC\_MODE values of 3 or 4 (decimate by 16 or 12), the delay is 16 to 18 samples. The delay associated with an ADC reset event is much shorter because it avoids the digital filter path. This delay is 1 sample for DEC\_MODE values of 1 or 2 and 2 samples for DEC\_MODE values of 3 and 4.



<span id="page-43-1"></span><span id="page-43-0"></span>



# **GPIO FUNCTIONALITY**

The AGCx pins can also be configured for basic GPIO functionality via Register 0x1B0 to Register 0x1B4. Register 0x1B0 determines which pins are used for GPIO functionality, whereas Register 0x1B1 determines if an AGC pin serves as input or output. If the pin serves as an output, Register 0x1B2 determines the high or low state, and Register 0x1B3 reads back the state of these designated output pins. Lastly, if an AGCx pin serves as an input, Register 0x1B4 reads back the state of this pin.

# **POWER SAVING MODES**

The [AD6676 f](http://www.analog.com/AD6676?doc=AD6676.pdf)eatures two SPI configurable and selectable power savings modes. The first mode is a sleep mode where th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) is placed in a low power state for extended periods, and the second mode is a standby mode where th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) enters a reduced power state but still keeps the JESD204B link and digital clocks active to ensure multichip synchronization (or fixed latency) during fast power cycling. Both sleep mode and standby mode can be entered via a SPI write operation to the PD\_MODE bits in the DEVICE\_CONFIG register (Register 0x002; Bits[1:0]). Note that, depending on whether sleep or standby mode is selected, various functional blocks within the Σ-Δ ADC itself are either powered down, placed in a low bias state, or remain powered.

The standby mode is also controllable via a user designated AGCx pin for faster and more precise power cycling. This feature is particularly useful for TDD-based communication protocols, allowing the host processor to quickly power cycle the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) during transmit bursts. The PD\_PIN\_CTRL register (Register 0x152) enables this feature as well as designates the AGC pin.

The standby register (Register 0x150) powers down different functional blocks during standby mode. However, all functional blocks that affect the clock generation, distribution and the JESD204B link remain enabled to maintain constant latency while in standby. The only exception is STBY\_VSS2GEN (Register 0x150, Bit 6) where a trade-off exists in power savings vs. wake-up time, depending on whether the negative voltage generator is placed in standby.

[Table 17](#page-43-1) shows the realized power savings for the different power savings modes at 3.0 GSPS operation with the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) configured for 125 MSPS IQ output and the internal clock synthesizer enabled. Note that STDBY\_FAST and STDBY\_SLOW correspond to whether the STBY\_VSS2GEN bit is enabled or disabled during standby. Note that an additional 18% power savings can be achieved when powering down the STBY\_VSS2GEN bit.

Although th[e AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)an enter into standby quickly, it does require a few microseconds to exit standby. [Figure 115 s](#page-44-0)hows that the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) can achieve a low power state within 100 ns. [Figure 116](#page-44-1) an[d Figure 117](#page-44-2) show the wake-up time between the STDBY\_FAST and STDBY\_SLOW cases to achieve 1% envelope settling accuracy being around 2.5 µs and 11.5 µs, respectively. The phase response is not shown because it settles faster than the envelope response. Note that the digital data path is enabled for these time domain figures such that the setting time responses can be observed.



<span id="page-44-0"></span>Figure 115. Fast Power-Down Response When th[e AD6676 I](http://www.analog.com/AD6676?doc=AD6676.pdf)s Placed in Standby



<span id="page-44-1"></span>Figure 116. Settling Time for STDBY\_FAST with the STBY\_VSS2GEN Enabled for Fastest Recovery, Approximately 2.5 μs to 1 %



<span id="page-44-2"></span>Figure 117. Settling Time for STDBY\_SLOW with STBY\_VSS2GEN in Standby for Additional Power Savings, Approximately 11.5 μs to 1 %

# **INTRODUCTION TO THE JESD204B INTERFACE**

The JESD204B interface reduces the PCB area for data interface routing yet enabling the use of smaller packages for converter and logic devices. The [AD6676 d](http://www.analog.com/AD6676?doc=AD6676.pdf)igital output complies with the JEDEC Standard No. JESD204B, Serial Interface for Data Converters. JESD204B is a protocol to link th[e AD6676 t](http://www.analog.com/AD6676?doc=AD6676.pdf)o a digital processing device over a serial interface. The [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) supports link rates of up 5.333 Gbps while operating with two output lanes in support of a maximum I/Q data rate  $(f_{DATAIQ})$ of 266.67 MSPS. Note that a two output lane configuration is always required for decimation factors of 12 and 16.

### **JESD204B Overview**

JESD204B data transmit block assembles the parallel data from the ADC into frames and uses 8-bit/10-bit encoding as well as optional scrambling to form serial output data. Lane synchronization is supported through the use of special characters during the initial establishment of the link and additional synchronization is embedded in the data stream thereafter. A JESD204B receiver is required to complete the serial link. For additional details on the JESD204B interface, refer to the JESD204B standard.

Because the [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)rovides 16-bit complex IQ data, its JESD204B transmit block effectively maps the output of two virtual ADCs ( $M = 2$ ) over a link. The link is configurable for either single or dual lanes with each lane providing a serial data stream via a differential output. The JESD204B specification refers to a number of parameters to define the link and these parameters must match between th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) JESD204B transmitter and receiver.

The following parameters describe a JESD204B link:

- S = samples transmitted per single converter per frame cycle ( $AD6676$  value = 1)
- M = number of converters per converter device [\(AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf)  $value = 2$
- $L =$  number of lanes per converter device [\(AD6676 v](http://www.analog.com/AD6676?doc=AD6676.pdf)alue can be 1 or 2)
- $N =$  converter resolution [\(AD6676 v](http://www.analog.com/AD6676?doc=AD6676.pdf)alue = 16)
- $N'$  = total number of bits per sample [\(AD6676 v](http://www.analog.com/AD6676?doc=AD6676.pdf)alue = 16)
- CF = number of control words per frame clock cycle per converter device  $(AD6676 \text{ value} = 0)$
- CS = number of control bits per conversion sample  $(AD6676 \text{ value} = 0)$  $(AD6676 \text{ value} = 0)$
- $K =$  number of frames per multiframe (configurable on the [AD6676 u](http://www.analog.com/AD6676?doc=AD6676.pdf)p to 32)
- $HD = high density mode (AD6676 value = 0)$  $HD = high density mode (AD6676 value = 0)$  $HD = high density mode (AD6676 value = 0)$
- $F =$  octets per frame [\(AD6676 v](http://www.analog.com/AD6676?doc=AD6676.pdf)alue = 2 or 4, dependent on  $L = 2$  or 1)
- $T = \text{tail bit} (AD6676 \text{ value} = 0)$  $T = \text{tail bit} (AD6676 \text{ value} = 0)$  $T = \text{tail bit} (AD6676 \text{ value} = 0)$
- SCR = scrambler enable or disable (configurable on the [AD6676\)](http://www.analog.com/AD6676?doc=AD6676.pdf)

[Figure 118](#page-45-0) shows a simplified block diagram of th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) JESD204B link mapping the 16-bit I and Q outputs onto the two separate lanes. Other configurations are also possible, such as combining the I and Q outputs onto a single lane ( $f_{DATA\_IQ}$   $\leq$ 153.6 MSPS) or changing the mapping of the I and Q output paths. In any case, the 16-bit I and Q data are each broken into two octets (eight bits of data). Bit 15 (MSB) through Bit 8 are in the first octet. The second octet contains Bit 7 through Bit 0 (LSB). The four resulting octets (2 I octets and 2 Q octets) may be scrambled. Scrambling is optional but is available to avoid spectral peaks when transmitting similar digital data patterns.

The scrambler uses a self synchronizing polynomial-based algorithm defined by the equation  $1 + x^{14} + x^{15}$ . The descrambler in the receiver must be a self synchronizing version of the scrambler polynomial.

The four octets are then encoded with an 8-bit/10-bit encoder. The 8-bit/10-bit encoder takes eight bits of data (an octet) and encodes them into a 10-bit symbol[. Figure 119 s](#page-45-1)hows how the 16-bit I or Q data is taken from the final decimation stage, formed into octets, the two octets are scrambled, and how the octets are encoded into two 10-bit symbols.

<span id="page-45-2"></span><span id="page-45-1"></span><span id="page-45-0"></span>

# **FUNCTIONAL OVERVIEW**

The flowchart i[n Figure 120 s](#page-45-2)hows the flow of data through the JESD204B hardware from the sample input to the physical output. The processing is divided into layers that are derived from the OSI model widely used to describe the abstraction layers of communications systems. These are the transport layer, the data link layer, and the physical layer (serializer and output driver).

# **Transport Layer**

The transport layer packs the data into JESD204B frames, which are mapped to 8-bit octets that are sent to the data link layer. The transport layer mapping is controlled by rules derived from the link parameters. The [AD6676 u](http://www.analog.com/AD6676?doc=AD6676.pdf)ses no tail bits in the transport layer because the output of its IQ digital data path is considered two virtual 16-bit converters.

# **Data Link Layer**

The data link layer is responsible for the low level functions of passing data across the link. These include optional data scrambling, inserting control characters for lane alignment/ monitoring, and encoding 8-bit octets into 10-bit symbols. The data link layer also sends the initial lane alignment sequence (ILAS), which contains the link configuration data, and is used by the receiver to verify the settings in the transport layer.

# **Physical Layer**

The physical layer consists of the high speed circuitry clocked at the serial clock rate. For the [AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) the 16-bit I and Q data are converted into one or two lanes of high speed differential serial data.

# **JESD204B LINK ESTABLISHMENT**

The [AD6676 J](http://www.analog.com/AD6676?doc=AD6676.pdf)ESD204B Tx interface operates in Subclass 0 or Subclass 1 as defined in the JEDEC Standard No. 204B (July 2011) specification. The link establishment process is divided into the following steps: code group synchronization, ILAS, and user data.

# **Code Group Synchronization (CGS) and SYNCINB**

Code group synchronization (CGS) is the process where the JESD204B receiver finds the boundaries between the 10-bit symbols in the stream of data. During the CGS phase, the JESD204B transmit (JESD Tx) block transmits /K28.5/ characters. The receiver must locate /K28.5/ characters in its input data stream using clock and data recovery (CDR) techniques.

The receiver issues a synchronization request by asserting a low signal on the SYNCINB± pins of the [AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) The JESD Tx begins to send /K/ characters. After the receiver has synchronized, it then deasserts its SYNCINB signal, causing it to go high. The [AD6676 t](http://www.analog.com/AD6676?doc=AD6676.pdf)hen transmits an ILAS on the following LMFC boundary.

For more information on the CGS phase, see the JEDEC Standard No. 204B (July 2011), Section 5.3.3.1.

The SYNCINB± pin operation options are controllable via SPI registers. Although the SYNCINB input is configured for a CMOS logic level on its positive pin by default, it can also be configured for a differential LVDS input signal on its positive/ negative pins via Register 0x1E7. The polarity of the SYNCINB input signal can also be inverted via Register 0x1E4.

# **Initial Lane Alignment Sequence (ILAS)**

The ILAS phase follows the CGS phase and begins on the next LMFC boundary. The ILAS consists of four multiframes, with a /R/ character marking the beginning and an /A/ character marking the end. The ILAS begins by sending an /R/ character followed by a data ramp starting with the value, 0, over four multiframes. On the second multiframe, the link configuration data is sent, starting with the third character. The second character in the second multiframe is a /Q/ character to confirm that the link configuration data follows. All undefined data slots are filled with ramp data. The ILAS sequence is never scrambled.

The ILAS sequence construction is shown i[n Figure 121.](#page-47-0) The four multiframes include the following:

- Multiframe 1: Begins with an /R/ character (/K28.0/) and ends with an /A/ character (/K28.3/).
- Multiframe 2: Begins with an /R/ character followed by a /Q/ (/K28.4/) character, followed by link configuration parameters over 14 configuration octets (see [Table 18\)](#page-47-1), and ends with an /A/ character. Many of the parameter values are of the notation of  $n - 1$ .
- Multiframe 3: Begins with an /R/ character (/K28.0/) and ends with an /A/ character (/K28.3/).
- Multiframe 4: Begins with an /R/ character (/K28.0/) and ends with an /A/ character (/K28.3/).

# **User Data and Error Detection**

After the ILAS is complete, the user data is sent. Normally, in a frame all characters are user data. However, to monitor the frame clock and multiframe clock synchronization, there is a mechanism for replacing characters with /F/ or /A/ alignment characters when the data meets certain conditions. These conditions are different for unscrambled and scrambled data. The scrambling operation is disabled by default, but may be enabled via Register 0x1C3.

For scrambled data, any 0xFC character at the end of a frame is replaced by an /F/ and any 0x7C character at the end of a multiframe is replaced with an /A/. The JESD204B receiver checks for /F/ and /A/ characters in the received data stream and verifies that they only occur in the expected locations. If an unexpected /F/ or /A/ character is found, the receiver uses dynamic realignment or asserts the SYNCINB± signal for more than four frames to initiate a resynchronization. For unscrambled data, if the final character of two subsequent frames is equal, the second character is replaced with an /F/ if it is at the end of a frame, and an /A/ if it is at the end of a multiframe.

Insertion of alignment characters may be modified using SPI. The frame alignment character insertion is enabled by default. More information on the link controls is available in the SPI register descriptions for Register 0x1E0 to Register 0x1E6.

# **8-Bit/10-Bit Encoder**

The 8-bit/10-bit encoder converts 8-bit octets into 10-bit symbols and inserts control characters into the stream when needed. The control characters used in JESD204B are shown in [Table 18.](#page-47-1) The 8-bit/10-bit encoding ensures that the signal is dc balanced by using the same number of ones and zeroes across multiple symbols. Note that the 8-bit/10-bit interface has an invert option available in Register 0x1E4 that has the same effect of swapping the differential output data pins.



Figure 121. Initial Lane Alignment Sequence

<span id="page-47-1"></span><span id="page-47-0"></span>



# **PHYSICAL LAYER INPUT/OUTPUTS**

# **Digital Inputs**

The [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)hysical layer consists of consists of two digital differential inputs, SYSREF± and SYNCINB±, whose equivalent input circuits are shown i[n Figure 61 a](#page-20-0)n[d Figure 64.](#page-20-1) These inputs must be dc-coupled to their respective drivers because they are or can be aperiodic. The SYNCINB± input is logic compliant to both CMOS and LVDS via Register 0x1E7, Bit 2, with CMOS being the default. Note that the SYNCINB± input includes an internal 100  $Ω$  termination resistor when LVDS is selected.

The optional SYSREF± input can be used for multichip synchronization or establishing a repeatable latency between the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) and its host. The SYSREF± receiver circuit must be disabled if not used (Register  $0x1E7 = 0x04$ ) to prevent potential false triggering if the input pins are left open. The SYSREF± input does not include an internal 100  $\Omega$  termination resistor; thus, an external differential termination resistor must be included if this input is used. The SYSREF± input is logic complaint to LVPECL, LVDS, and CMOS.

# **Digital Outputs, Timing and Controls**

The [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)hysical layer consists of digital drivers that are defined in the JEDEC Standard No. 204B (July 2011). These CML drivers are powered up by default via Register 0x1E2. The drivers utilize a dynamic 100  $\Omega$  internal termination to reduce unwanted reflections. A 100 Ω differential termination resistor at each receiver input results in a nominal 300 mV p-p swing at the receiver.

The [AD6676 J](http://www.analog.com/AD6676?doc=AD6676.pdf)ESD204B differential outputs can interface with custom ASICs and FPGA receivers, providing superior switching performance in noisy environments. Single point-to-point network topologies are recommended with receiver inputs having a nominal differential 100 Ω termination. The common mode of the digital output automatically biases itself to half the VDDHSI supply of 1.1 V (VCM =  $0.55$  V), thus making ac coupling the preferred coupling method to the receiver logic as shown [Figure 122.](#page-48-0) DC coupling can be considered if the receiver device shares the same VDDHSI supply and input common-mode range.





<span id="page-48-0"></span>Timing errors caused by a degraded eye diagram at the receiver input can often be attributed to poor far end termination or differential trace routing. These potential error sources can be reduced by using well controlled differential 100  $\Omega$  traces with lengths below six inches that connect to receivers with integrated differential 100  $\Omega$  resistors.

[Figure 123,](#page-48-1) [Figure 124,](#page-48-2) an[d Figure 125](#page-48-3) show examples of the digital output data eye, time interval error (TIE) jitter histogram, and bathtub curve for on[e AD6676 l](http://www.analog.com/AD6676?doc=AD6676.pdf)ane running at 5.333 Gbps with Register 0x1EC set to 0xBD. The format of the output data is twos complement by default. The output data format can be changed via Register 0x146.



<span id="page-48-1"></span>Figure 123. Digital Outputs Data Eye with External 100  $\Omega$  Terminations at 5.333 Gbps in Accordance to LV-OIF-11G-SR Mask



<span id="page-48-2"></span>Figure 124. Digital Outputs Histogram with External 100 Ω Terminations at 5.333 Gbps



<span id="page-48-3"></span>Figure 125. Digital Outputs Data Bathtub with External 100 Ω Terminations at 5.333 Gbps

# **Preemphasis**

Preemphasis enables the receiver eye diagram mask to be met in conditions where the interconnect insertion loss does not meet the JESD204B specification. The preemphasis feature is controlled via Register 0x1EF and must be used only when the receiver cannot recover the clock due to excessive insertion loss. Under normal conditions, it is disabled to conserve power. Additionally, enabling and setting too high a deemphasis value on a short link may cause the receiver eye diagram to fail or lead to potential EMI issues. For these reasons, consider the use of preemphasis only in instances where meeting the receiver eye diagram mask is a challenge. See th[e Register Memory Map s](#page-65-1)ection for details.

# **Serializer PLL**

This PLL generates the serializer clock that is equal to the JESD204B lane rate. The on-chip controller automatically configures the PLL parameters based on the user specified IQ data rate  $(F<sub>ADC</sub>/M)$  and number of lanes. The status of the PLL lock can be checked via the PLL\_LCK status bit in Register 0x2DC. This read only bit lets the user know if the PLL has achieved a lock for the specific setup.

# **CONFIGURING THE JESD204B LINK**

The [AD6676 h](http://www.analog.com/AD6676?doc=AD6676.pdf)as one JESD204B link. The serial outputs (SERDOUT0± and SERDOUT1±) are part of one JESD204B link. The basic parameters that determine the link setup are:

- L is the number of lanes per link
- M is the number of converters per link
- F is the number of octets per frame

The maximum and minimum specified lane rates for the [AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)re 5.333 Gbps and 3.072 Gbps, respectively. For this reason, th[e AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)upports a single lane interface for IQ data rates (f<sub>DATA\_IQ</sub>) from 76.8 MSPS to 133.3 MSPS and a two lane interface from 153.6 MSPS to 266.7 MSPS.

The lane line rate is related to the JESD204B parameters using the following equation:

$$
Lane Line Rate = \frac{(40 \times F_{\text{DATA},10})}{L}
$$
 (14)

where:

$$
F_{\text{data\_IQ}} = \frac{F_{\text{ADC}}}{DEC}
$$

The decimation ratio (DEC) is the parameter programmed into Register 0x140.

[Table 19 s](#page-49-0)hows the JESD204B output configurations supported based on  $f_{\text{DATA IO}}$ .



### <span id="page-49-0"></span>**Table 19. JESD204B Output Configurations**

# <span id="page-50-0"></span>**SYNCHRONIZATION USING SYSREF±**

Th[e AD6676 u](http://www.analog.com/AD6676?doc=AD6676.pdf)ses the SYSREF± input to provide synchronization for the JESD204B serial output and to establish a fixed phase reference for the decimation filters and the NCO within the QDDC. Synchronization options are configurable via Register 0x1E8. When initially synchronizing, the absolute phase offset relative to the input clock applied to the CLK± pins depends on internal clock phases and therefore has an uncertainty of  $\pm 1$  ADC clock cycles.

A clock tree diagram is shown i[n Figure 126 w](#page-50-1)ith an internal clock signal, DIG\_CLK, used to ultimately sample the SYSREF± signal. Note that the SYSREF± setup and hold times are defined with respect to the rising SYSREF± edge and rising CLK± (or CLK+ with the clock synthesizer disabled) edge, as shown in [Figure 2.](#page-7-0) After the SYSREF± signal is sampled, the phase remains locked to the same relative internal ADC\_CLK phase offset until th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) is intentionally reset or its clock or power interrupted.

Note the following considerations when using SYSREF± for synchronization.

- The SYSREF± pulse width must be at least two ADC\_CLK periods.
- Bit 3 of Register 0x2BB must be set low when synchronizing with the clock synthesizer enabled. In this case, that SYSREF± is sampled on the rising edge of REF\_CLK to allow for significant margin in setup and hold time. This synchronization signal is then sampled again with the internally generated DIG\_CLK.
- Because SYSREF± is ultimately sampled with an internal clock greater than 1 GHz, it can be difficult to maintain synchronization of the clock and SYSREF± distribution in a system over supply and temperature variations, as well as

cumulative jitter affects. Use the one shot with the second SYSREF pulse to avoid unnecessary resetting of the JES204B link by setting Register 0x1E8 to 0x06. A minimum of two SYSREF pulses are required.

- The coarse and fine digital NCOs can be reset to an initial phase defined in Register 0x143 through Register 0x145 upon receiving SYSREF±. For the recommended one shot with the second SYSREF pulse, set Register 0x1E8 to 0x26 so that the same SYSREF pulse that is used to reset the JESD204 internal dividers is used to reset the NCO phases.
- If continuous SYSREF± is still preferred, it is recommended to use the SYSREF\_WIN\_NEG and SYSREF\_WIN\_POS bits in Register 0x1EA to allow for slight variation in SYSREF± timing relative to DIG\_CLK.
- A phase variance of ±1 ADC clock cycles ultimately results in fractions of a sample when referenced to the IQ output data rate, fDATA\_IQ, depending on the decimation factor. For example, for a decimation factor of 32, the phase uncertainty is expressed as  $\pm 1/32$  samples relative to  $f_{DATA\_IQ}$ .
- The course and fine digital NCOs are also set to an initial phase up defined in Register 0x143 thru Register 0x145 upon receiving SYSREF±.
- [Figure 127](#page-51-0) shows how the [HMC7044 \(](http://www.analog.com/HMC7044?doc=AD6676.pdf)or th[e AD9528\)](http://www.analog.com/AD9528?doc=AD6676.pdf) can be used for mulichip synchronization. Th[e HMC7044 i](http://www.analog.com/HMC7044?doc=AD6676.pdf)s best suited for delivering a low phase noise RF clock source for eac[h AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) (refer t[o Figure 135\)](#page-55-0). In addition, its ability to individually control the delays of both the CLK and SYSREF signals to each [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) device allows compensation of PCB skew delays.



<span id="page-50-1"></span>Figure 126. Block Diagram Showing Options of Sampling the SYSREF Input Signal with the Clock Synthesizer Disabled or Enabled



<span id="page-51-0"></span>Figure 127. Example of Multichip Synchronization of th[e AD6676 U](http://www.analog.com/AD6676?doc=AD6676.pdf)sing th[e HMC7044 o](http://www.analog.com/HMC7044?doc=AD6676.pdf)r th[e AD9528](http://www.analog.com/AD9528?doc=AD6676.pdf)

# APPLICATIONS INFORMATION **ANALOG INPUT CONSIDERATIONS**

# **Equivalent Input Impedance and S11**

The [AD6676 b](http://www.analog.com/AD6676?doc=AD6676.pdf)enign input structure along with its low drive level requirements facilitates interfacing it to external driver circuitry[. Figure 128 s](#page-52-0)hows the equivalent parallel impedance for attenuator settings of 0 dB and 6 dB. Note that the slight variation in impedance between the different attenuator settings is an error source affecting the absolute accuracy of the attenuator settings. Th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) input also displays excellent S11 return loss over a wide frequency range, as shown in [Figure 94.](#page-33-0) 



<span id="page-52-0"></span>Figure 128. Typical Equivalent Parallel Impedance of AIN for Attenuator = 0 and 6 dB Settings

# **Input Driver and Filter Considerations**

The input driver requirements, along with any additional filtering, are application dependent. Additional filtering maybe considered if any large signal content or blockers falling above or below the IF pass band of interest can cause desensitization by either increasing the ADC noise or spur floor. Below the IF pass band, the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s most sensitive to second harmonic content that is typically induced by the driver stage itself due to its limited IP2 performance. The [AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)econd-order nonlinearity contribution is typically on par with a balanced mixer and well below the contribution of a single-ended amplifier stage (with output balun) used for VHF applications. [Table 20](#page-52-1)  shows the measured  $f_1 + f_2$  spurious level and equivalent IIP2 for different IFs when dual tones are injected at −6 dBFS levels and at IF/2.

$1111$ value of level is oftended at $11/2$										
IF (MHz)	<b>LEXT</b> (nH)	PIN OdBFS (dBm)	<b>Dual Tone</b> <b>Input Power</b> (dBm)	$f_1 + f_2$ Spur (dBc)	<b>Equivalent</b> $IP2$ (dBm)					
200	43	$-2.5$	$-8.5$	$-69.5$	61					
250	19	$-2.2$	$-8.2$	$-68.3$	60					
300	19	$-2.2$	$-8.2$	$-73$	65					
350	10	$-2.2$	$-8.2$	$-66.3$	58.5					
400	10	$-2.2$	$-8.2$	$-68.5$	60					

<span id="page-52-1"></span>**Table 20. Harmonic Levels When Dual Tones = −6 dBFS of PIN\_0dBFS Level is Situated at IF/2** 

Above the IF pass band, th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) is sensitive to high frequency blockers that can increase the noise floor due to jitter or generate an image component that falls back into the pass band. Th[e AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s also fairly insensitive to spurious tones falling in the alias regions occurring at  $F_{ADC} \pm F_{IF}$  because th[e AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)rovides over 50 dB of alias rejection[. Table 21](#page-52-2) shows the typical alias rejection for different FADC and IF combinations. Because mixers often produce fixed large spurious at  $M \times LO$  as well as its sum term of  $LO +$ F<sub>RF</sub>, determine if any of these spurs can fall in the alias regions and if so, add the appropriate level of filtering to suppress them below the receivers required spurious level.

<span id="page-52-2"></span>**Table 21. Typical Alias Rejection for Different IF and ADC Combinations** 

$F_{ADC}$ (MHz)	IF (MHz)	$F_{ADC}$ – IF Alias <b>Rejection (dBc)</b>	$F_{ADC}$ + IF Alias <b>Rejection (dBc)</b>
2000	150	58	59
2400	200	53	54
2800	300	51	59
3200	400	51	59

Because the required attenuation of out-of-band signal signals is application dependent, evaluate the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) under the desired application conditions to understand the effects and determine what amount of filtering is required. In practice, a simple thirdorder low-pass roofing filter can provide adequate additional suppression against spurs falling in the alias regions as well as large signal signals falling a few 100 MHz above the IF pass band. Note that the [AD6676EBZ i](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)ncludes an optional 500 MHz third-order low-pass filter (TDK MEA1210D501R) that may suffice for many applications. This small, 0302 size differential filter is also available with lower frequency options. Its effect on the pass band flatness is mimimal but provides provides additional suppression beyond 700 MHz. as shown in [Figure 129](#page-53-0) as well as in the alias region as shown i[n Table 22.](#page-53-1)



<span id="page-53-1"></span><span id="page-53-0"></span>



A 1:1 balun is required in applications where the last amplification stage is single-ended with a  $Z_{\text{OUT}}$  of 50  $\Omega$ . This is typically the case in a VHF receiver application where a gain block, such as the [ADL5541 t](http://www.analog.com/ADL5541?doc=AD6676.pdf)o [ADL5545 s](http://www.analog.com/ADL5545?doc=AD6676.pdf)eries, precedes the [AD6676 f](http://www.analog.com/AD6676?doc=AD6676.pdf)or preamplification.



Figure 130. RF Line-Up for Direct Sampling VHF Application For many RF receiver applications, this differential signal may originate from a RF-to-IF mixer whose output impedance often falls within a 50  $\Omega$  to 200  $\Omega$  range. A low order matching network that also serves as a low-pass roofing filter can compensate for the mismatch impedance. It is worth noting that the impedance mismatch between a source/load mismatch of 200  $\Omega$ /60  $\Omega$  and 100  $Ω/60 Ω$  is approximately 1.5 dB and 0.3 dB, respectively. This low mismatch loss may be tolerable for some applications seeking a wide, low ripple IF pass band, especially considering the loss of a higher order matching network with finite Q components. Lastly, it is possible to reduce the ADC maximum input power requirements slightly to compensate for this low loss with minimal loss in dynamic range.

Other receiver applications in the VHF band may prefer that th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) directly digitize the signal. Typically, the radio lineup may include a low NF gain block whose single-ended output is converted to a differential output via an ac-coupled balun. The amplitude/phase balance requirements of balun can be relaxed (compared to traditional pipeline ADCs) because the even order

harmonics that are sensitive to balance fall outside the pass band. Note that the second harmonic of the gain block still must fall outside the VHF pass band so that it can also be digitally filtered.

Some additional considerations pertaining to the analog input are as follows:

- AC coupling with 10 nF or greater capacitors to the VIN± input is required to a maintain 1 V common-mode voltage. Note that this capacitor provides a high-pass response with the [AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) input impedance and thus must be sized accordingly for low IF applications to prevent excessive droop on the lower pass band response.
- A series 10  $\Omega$  resistor and 0.1 µF decoupling capacitor is recommended between the 2.5 V supply and first resonators to provide additional filtering of supply induced noise and ADC common-mode currents.
- The feedback DAC (operating up to 3.2 GHz) also generates high frequency content (that is, images, clock feedthrough and shaped noise) that is ideally absorbed by the internal source follower. Due to its finite impedance at the higher frequencies, a small amount of this undesired signal content leaks through the attenuator path back to the VIN± input. Passive mixers are particularly susceptible to this signal content due to poor isolation between the IF and RF ports while passive mixers with on-chip IF amps and active mixers provide a greater degree of reverse isolation. A simple third-order roofing filter typically provides sufficient rejection to suppress these ADC artifacts while also suppressing the larger  $M \times N$  artifacts of the mixer. Note that this filter must be designed as two single-ended, pi network filters with shunt capacitors located next to the VIN $\pm$  pins to steer this undesired signal content to ground. Also, use care in component selection and layout to reduce parasitics that can cause unanticipated peaking in the stop-band region of the filter response.

# **CLOCK INPUT CONSIDERATIONS**

The  $AD6676$  Σ-Δ ADC operates with an internal ADC clock rate (FADC) between 2.0 GSPS to 3.2 GSPS. The clock signal can originate from an external clock source or, alternatively, from its on-chip clock synthesizer. Consider an external clock source if the on-chip synthesizer phase noise or spurious level is not deemed sufficient or if the desired F<sub>ADC</sub> falls below the 2.94 GHz to 3.2 GHz range of the VCO. Referring t[o Figure 60,](#page-20-2) the selfbiased clock receiver is configured as either a differential or singleended receiver, depending on whether the clock synthesizer is disabled. In either case, the external clock source must be ac coupled to th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) CLK± input and meet the minimum specified input level and slew rate. Also, clock jitter and phase noise must always be a concern in selecting the clock source.

When the clock synthesizer is enabled, the CLK± inputs are connected to CMOS inverters as shown in [Figure 60.](#page-20-2) These inverters are self-biased at approximately 0.55 V and present an input resistance exceeding 1.2 kΩ when Bit 2 of Register 0x2BB is set.

A single-ended clock source need only be ac coupled to the CLK+ input because the inverter output for CLK− input is not used. For CMOS drivers, the addition of a 33  $\Omega$  series resistor is recommended to dampen the response for long trace lengths. For a differential clock source, such as an LVDS or PECL source, the addition of a 100 Ω external termination resistor across the CLK± pins is recommended to minimize any reflections that result from distorting the clock input waveform.

When the clock synthesizer is disabled, the CLK± inputs are connected to a high speed differential clock receiver with on-chip 100 Ω termination to simplify interfacing to CML, LVPECL, or sinusoidal clock sources. The clock signal is typically ac-coupled to the CLK+ and CLK− pins via an RF balun or capacitors. These pins are biased internally (se[e Figure 60\)](#page-20-2) at approximately 700 mV and require no external bias. The equivalent shunt impedance of the CLK± input is shown i[n Figure 131.](#page-54-0) It is recommended to use a 100  $\Omega$  differential transmission line to route the clock signal to the CLK+ and CLK− pins due to the high frequency nature of the signal.



<span id="page-54-0"></span>Figure 131. Equivalent Shunt Differential Input Impedance of the CLK± Pins with the Clock Synthesizer Disabled

[Figure 132](#page-54-1) shows a single-ended clock solution for th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) when its clock synthesizer is disabled. The low phase noise singleended source can be from an external VCXO. A ceramic RF chip 1:2 ratio balun creates the differential clock input signal. The balun must be specified to have low loss (that is, less than 2 dB) at the clock frequency of interest. The single-ended clock source must be capable of 0 dBm drive capability to ensure adequate signal swing into the clock input.



<span id="page-54-1"></span>Figure 132. Balun Coupled Differential Clock

A single-ended CMOS or differential ac-coupled PECL/HSTL clock signal can be delivered via clock generation and distribution ICs such as the Analog Device[s HMC7044,](http://www.analog.com/HMC7044?doc=AD6676.pdf) [AD9528,](http://www.analog.com/AD9528?doc=ad6676.pdf) and [ADCLK925.](http://www.analog.com/ADCLK925?doc=ad6676.pdf) A PECL clock signal is recommended when providing an RF clock input signal to th[e AD6676 o](http://www.analog.com/AD6676?doc=AD6676.pdf)r in applications that require deterministic latency or synchronization while using the internal clock synthesizer of th[e AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) [Figure 133 s](#page-54-2)hows a simple differential interface in which th[e AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)nterfaces to the PECL output available from these ICs. The [HMC7044](http://www.analog.com/HMC7044?doc=AD6676.pdf) is an excellent choice for JESD204B clock generation and multichip synchronization because it also generates a very low phase noise RF clock from 2.4 GHz to 3.2 GHz for multipl[e AD6676 d](http://www.analog.com/AD6676?doc=AD6676.pdf)evices.



<span id="page-54-2"></span>Figure 133. Differential PECL Sample Clock Using th[e HMC7044,](http://www.analog.com/HMC7044?doc=AD6676.pdf) [AD9528,](http://www.analog.com/AD9528?doc=ad6676.pdf) and [ADCLK925](http://www.analog.com/ADCLK925?doc=ad6676.pdf)

Alternatively, PLL clock synthesizers with on-chip VCOs such as th[e ADF4351,](http://www.analog.com/ADF4351?doc=AD6676.pdf) th[e ADF4355-2,](http://www.analog.com/ADF4355-2?doc=AD6676.pdf) an[d HMC1034](http://www.analog.com/HMC1034?doc=AD6676.pdf) also make excellent RF clock sources when multichip synchronization is not required. The CML outputs of these devices allow a simple interface as shown in [Figure 134.](#page-54-3) [Figure 135 c](#page-55-0)ompares the close in phase noise between the [ADF4351,](http://www.analog.com/ADF4351?doc=AD6676.pdf) the [ADF4355-2,](http://www.analog.com/ADF4355-2?doc=AD6676.pdf) the [HMC7044,](http://www.analog.com/HMC7044?doc=AD6676.pdf) th[e AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)lock synthesizer, and the R&S SMA100A for a near full-scale sine wave at 300 MHz. Note that the phase noise improvement offered by the high quality RF generator only becomes evident below 400 kHz when compared to th[e ADF4351.](http://www.analog.com/ADF4351?doc=AD6676.pdf)



<span id="page-54-3"></span>Figure 134. Differential CML Driver from th[e ADF4351 a](http://www.analog.com/ADF4351?doc=AD6676.pdf)nd th[e ADF4355-2](http://www.analog.com/ADF4355-2?doc=AD6676.pdf)



<span id="page-55-0"></span>Figure 135. Close In Phase Noise Comparison for Different Analog Devices Clock Sources when Compared to the R&S SMA100A and th[e AD6676 C](http://www.analog.com/AD6676?doc=AD6676.pdf)lock Synthesizer (IF = 300 MHz, BW = 40 MHz,  $F_{ADC}$  = 3.2 GHz, L = 19 nH)

12348-080

# **IF FREQUENCY PLANNING**

The Σ-Δ ADC can achieve exceptional SFDR performance over a wide IF frequency range because its high oversampling ratio prevents low order harmonics from aliasing into the IF pass band. Higher order harmonics that do alias back are typically of much lower magnitude, with the shuffling option further reducing their levels. However, finite isolation between the Σ-Δ ADC and the digital block causes additional spurious signals that are a function of the output data rate,  $f_{DATA_IQ}$ , and input frequency, f<sub>IN</sub>. Specifically, the feedback DACs in the Σ-Δ ADC suffer from digital contamination of its clock signal. Therefore, the same equation used to predict spurious locations on high speed DACs with digital interpolation filters applies.

Equation 15 defines this relationship with the spur location falling at f<sub>MN</sub>.

$$
f_{MN} = \pm (M \times f_{\text{DATA\_IQ}}) \pm (N \times f_{\text{IN}}) \tag{15}
$$

where:

M is the digital induced harmonic content from internal clocks. N is the harmonics from the Σ-Δ ADC.

When  $N = 0$ , signal independent spurs fall at integer multiples of  $f_{DATA\_IQ}$ [. Table 23](#page-55-1) shows the measured  $M \times f_{DATA\_IQ}$  spurious levels (dBFS) for different IF frequencies and decimation factors with f $_{\text{DATA\_IQ}}$  equal to 100 MSPS and 200 MSPS. All of the M  $\times$  $f<sub>DATA_IQ</sub>$  regions display low spurious with the exception of 200 MHz. This is because a large portion of digital circuitry is clocked at FADC/16 for DEC\_MODES of 1 and 3 or FADC/12 for DEC\_MODES of 2 and 4. As a result, the  $M = 2$  spur is dominant when operating at the higher decimation factors of 32 and 24 whereas the  $M = 1$  spur is dominant when operating at the lower decimation factors of 16 and 12.

When  $N = 1$ , signal dependent spurs falls at integer multiples of  $f_{DATA\_IQ}$ . These  $M \times N$  spurs are called images because they have a 1:1 relationship in amplitude and frequency with the input signal,  $f<sub>IN</sub>$ . Note that the magnitude of some images can also vary slightly between power cycles, due to different phase relationships among internal clock dividers upon device initialization.

Figure 136 shows a normalized image graph (relative to  $f_{\text{DATA IO}}$ ) showing the image location relative for a given input frequency.

When  $N > 1$ , spurious content is often at lower magnitude than other spurious thus often can be ignored. The exception is when  $f_{IN}$  falls below the IF pass band such that its lower order harmonics may fall within the pass band (that is, IF/2 and IF/3).



<span id="page-55-2"></span>Figure 136. Image Location for Different M Factors Normalized to f<sub>DATA\_IQ</sub>

<span id="page-55-1"></span>**Table 23. Measured Spurious Levels at Different IFs Where M × fDATA\_IQ Falls On for fDATA\_IQ of 100 MSPS and 200 MSPS** 

	<b>Spurious Levels (dBFS)</b>					
	$IF =$	$IF =$	$IF =$	$IF =$		
<b>f</b> DATA_IQ	<b>100 MHz</b>	<b>200 MHz</b>	300 MHz	<b>400 MHz</b>		
<b>100 MSPS</b>						
$DEC$ MODE = 1	$<-100$	$-81$	$\le -110$	$-97$		
$DEC MODE = 2$	$-100$	$-79$	$<-110$	N/A <sup>1</sup>		
<b>200 MSPS</b>						
DEC MODE = $3$	$<-110$	$-81$	$<-110$	$-90$		
DEC MODE = $4$	$<-110$	$-77$	$<-110$	N/A <sup>1</sup>		

<sup>1</sup> N/A means not applicable.

Because the image spurs are also at low levels, the [AD6676 o](http://www.analog.com/AD6676?doc=AD6676.pdf)ffers a wide range of suitable IFs for a given output data rate, fDATA\_IQ. Even IFs that are situated in a region where the worst  $M \times f_{\text{DATA\_IQ}}$ spurious condition described i[n Table 23](#page-55-1) can be used because they remain at a fixed location and remain signal independent. Similar to the LO feedthrough issue in a direct conversion IQ receiver, a slow digital tracking loop in the host processor can be used to nullify it[. Figure 137 a](#page-56-0)n[d Figure 138 s](#page-56-1)how a case where the IF of 200 MHz was selected for an  $f_{\text{DATA IO}}$  to  $f$  200 MSPS and 100 MSPS such that dominant spur falls exactly at the IF center. As shown in [Figure 136,](#page-55-2) the IF is positioned at a normalized fDATA\_IQ of 1 or 2 for 200 MSPS and 100 MSPS operation, thus explaining why the image term is  $M = 2$  or 4. Note that the image spur is quite low for  $M = 2$  and can be further improved by selecting a higher decimation factor (DEC\_MODE of 3 vs. 1) that results in the  $M = 4$  image.



<span id="page-56-0"></span>Figure 137. Image Spur for  $f_{DATA_Q} = 200$  MSPS (DEC\_MODE = 3) Attributed to  $M = 2, N = -1$ 



<span id="page-56-1"></span>Figure 138. Reduction in Image Spur When  $f_{DATA}$   $_{10}$  is Reduced to 100 MSPS

IF pass band regions that remain free of any of these spurs exist in the following regions for a swept input tone across its pass band:

$$
(M-0.5) \times f_{\text{DATA\_IQ}} < IF \text{ Pass Band} < M \times f_{\text{DATA\_IQ}} \tag{16}
$$

Or

 $M \times f_{\text{DATA\_IQ}} < I$ F Pass Band  $< (M + 0.5) \times f_{\text{DATA\_IQ}}$  (17)

Note that because these spur free regions have a bandwidth of  $0.5 \times$  f<sub>DATA\_IQ</sub>, it is often desirable to use a higher f<sub>DATA\_IQ</sub> rate (that is, lower decimation factor) to support larger IF bands[. Figure 139](#page-56-2)  shows a spur free region swept SFDR less than −95 dBFS with  $f_{DATA\_IQ} = 200$  MSPS and BW = 100 MHz with the IF now centered at 250 MHz. Selecting an IF situated at 350 MHz and BW = 100 MHz also produces similar results.



<span id="page-56-2"></span>Figure 139. Digital Induced Spurs for an IF That Is Centered Between fDATA\_IQ and  $1.5 \times f_{DATA\_IQ}$  with  $f_{DATA\_IQ} = 200$  MSPS

# **PCB DESIGN GUIDELINES**

The design of the PCB is critical in achieving the full performance of the [AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) The [AD6676EBZ e](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)valuation board, used for characterizing th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) ac performance, serves as an example of a possible layout that uses 0.1 mm (4 mil) through-hole vias under the device[. Figure 140 s](#page-57-0)hows the top side PCB layout of the region surrounding the [AD6676 w](http://www.analog.com/AD6676?doc=AD6676.pdf)here all the critical analog input/ outputs, digital input/outputs, and passive components reside. An alternative top side layout is shown i[n Figure 141 t](#page-57-1)hat avoids any through-hole vias under the device. Because this modified layout resulted in only a slight degradation in IMD performance, consider this layout option if via placement under the device is not possible.

Note the following:

- The PCB is a 6-layer board (1.6 mm thick) based on FR4 dielectric that avoids any expensive options, such as micro, hidden or blind vias, thus allowing cost effective manufacturing.
- Critical analog and digital high speed signal paths are routed on the first layer with controlled impedances. The lower speed CMOS digital input/outputs are placed on the back side sixth layer.
- A single solid ground plane is used as the second layer underneath th[e AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) The dielectric spacing is 8 mil to establish controlled impedances with the critical signal layer above.

The third and fourth layers are dedicated power planes used to isolate the differen[t AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) supply domains, and the fifth layer is a solid ground plane. The dielectric spacing between the second and third layer and the fourth and fifth layer is 3 mil to increase the distributed decoupling capacitance for each supply domain.

 Special consideration was given to via placement, ground fill, and power supply plane layout to main low thermal and electrical impedances.

# AD6676 Data Sheet

- All critical passive components, such as dc blocking and power supply decoupling capacitors, are 0201 size and placed on top side of the PCB. Two 0201 decoupling capacitors  $(0.001 \,\mu\text{F}$  and  $0.1 \,\mu\text{F})$  are placed adjacent to supply pins with the lower value placed closer to th[e AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf)
- The analog 1.1 V supply pins of th[e AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)hare a common 1.1 V supply domain and are tied together below the device.
- VSS2OUT (Pin G7) must be connected to VSS2IN (Pin F6) on the top side layer of the PCB.
- The alternative layout shown i[n Figure 141 u](#page-57-1)ses 0.2 mm through-hole vias just outside of the [AD6676 p](http://www.analog.com/AD6676?doc=AD6676.pdf)ackage for all supply and ground domains with all of the 1.1 V analog supply domains (VDD1, VDDL, VDDC, and VDDQ) connected to each other providing a low impedance path to the critical inner VDD1 and VDDL balls. This alternative layout also avoids any narrow signal traces to inner row balls (with exception of CSB) by using a 3-wire SPI interface (with the SDIO, RESETB, AGC4, and AGC3 balls left open). Note that the thin inner trace for CSB (positioned between the SCLK and SYNCINB− balls) could have been avoided by running a wider straight trace instead of connecting the CSB and SYNCINB− balls because, by default, the SYNCINB input is configured for a CMOS input with only SYNCINB+ used for signaling (and SYNCINB− ignored).



Figure 140. [AD6676EBZ P](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)CB Top Side Layout Example

<span id="page-57-0"></span>

<span id="page-57-1"></span>Figure 141. Alternative PCB Top Side Layout Example That Avoids a Through Hole Via under the Device

Additional information specifically pertaining to the WLCSP package considerations is contained in the [AN-617 Application](http://www.analog.com/AN-617?doc=AD6676.pdf)  [Note.](http://www.analog.com/AN-617?doc=AD6676.pdf) This application note covers PCB design guidelines, assembly, reliability, and rework in detail.

# **POWERING TH[E AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf)**

The [AD6676 r](http://www.analog.com/AD6676?doc=AD6676.pdf)equires the following analog and digital power supplies with no restrictions on the power supply sequencing order:

- An analog 2.5 V and 1.1 V supply
- A digital 1.1 V and digital input/output supply of 1.8 V to 2.5 V

The current consumption from the different analog and digital supply domains does not vary much over the specified 2.0 GHz to 3.2 GHz ADC clock rate range nor the digital decimation factor and number of JESD204B lanes used[. Table 24 s](#page-58-0)hows the dependency of a typical device as these settings are modified with the IF and BW remaining fixed at 250 MHz and 75 MHz, respectively.

[Figure 142](#page-58-1) shows the recommended method used on the [AD6676EBZ w](http://www.analog.com/AD6676EBZ?doc=AD6676.pdf)here a universal 3.3 V supply is available. Note that various analog and digital supply domains within the [AD6676 a](http://www.analog.com/AD6676?doc=AD6676.pdf)re grouped together to reduce the external LDO requirements. A high efficiency step-down regulator, such as the [ADP2164,](http://www.analog.com/ADP2164?doc=AD6676.pdf) is used to generate a 1.6 V output that drives separate low drop-out LDOs for the analog VDD1 and digital VDDD supplies.



Figure 142. Low Noise Power Solution for th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf)

<span id="page-58-1"></span>Separate LDOs for the 1.1 V analog and digital supplies provide greater isolation between these critical supply domains as well as reduce the IR drops across ferrite beads that provide further isolation. High quality LDOs that exhibit better PSSR characteristics at the switching regulators operating frequency are preferable. Note that the digital VDDIO supply of the [AD6676 i](http://www.analog.com/AD6676?doc=AD6676.pdf)s only used for the CMOS SPI and AGCx input/output pins thus it can be tied to the same supply domain used by the host that is connected to these pins. Alternatively, th[e ADP223](http://www.analog.com/ADP223?doc=AD6676.pdf) dual output LDO can be used instead of the [ADP1752-2.5](http://www.analog.com/ADP1752?doc=AD6676.pdf) an[d ADP1752-1.8.](http://www.analog.com/ADP1752?doc=AD6676.pdf)

On the analog 1.1 V supply, amplitude modulation can result in phase modulation via the clock supplies of th[e AD6676 \(](http://www.analog.com/AD6676?doc=AD6676.pdf)VDDC, VDDQ).



# <span id="page-58-0"></span>Table 24. Current Consumption Variation as FADC Is Varied from 3.2 GHz to 2.0 GHz

[Figure 143](#page-59-0) an[d Figure 144](#page-59-1) show the measured sideband level in dBc that results if a 1 mV p-p continuous wave tone has frequencies common among switching regulators are injected onto the 1.1 V and 2.5 V analog supplies. Note that the sideband level increases at roughly 6 dB per octave in IF frequency for the 1.1 V supply domain case because the supply noise results in PM modulation that affects the clock jitter.



<span id="page-59-0"></span>Figure 143. Sideband Spur Level for 1 mV p-p, Continuous Wave Tone Injected on Analog 1.1 V Supply Domain



<span id="page-59-1"></span>Figure 144. Sideband Spur Level for 1 mV p-p, Continuous Wave Tone Injected on Analog 2.5 V Supply Domain

On the digital 1.1 V supply, amplitude modulation on the JESD204B high speed serializer supply (VDDHSI) can negatively impact the eye opening of the digital data output stream. For these reasons, low noise LDOs, such as the [ADP1752,](http://www.analog.com/ADP1752?doc=AD6676.pdf) that have a worst-case accuracy of 2% over line, load, and temperature are used for the analog VDD2 and VDD1 supplies. The same regulator is used for the digital VDDD for its low dropout characteristics, power supply rejection ratio, and load capability. Although the digital VDDD is used for the less critical VDDIO supply, a smaller, lower cost regulator such as the [ADP121,](http://www.analog.com/ADP121?doc=AD6676.pdf) can also be used to supply 1.8 V.

# **[AD6676 S](http://www.analog.com/AD6676?doc=AD6676.pdf)TART-UP INITIALIZATION**

On power-up of th[e AD6676,](http://www.analog.com/AD6676?doc=AD6676.pdf) a host processor is required to initialize and configure th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) via its SPI port. [Figure 145](#page-60-0)  shows a flowchart of the sequential steps required to bring the [AD6676 t](http://www.analog.com/AD6676?doc=AD6676.pdf)o an operational state. The number of SPI writes and total initialization time is dependent on whether the clock synthesizer is used, as well as any additional configuration associated with the AGC features or its pin configurations. Note that wait states are required during different steps in the initialization process to allow various actions, such as calibration and tuning, to be completed before moving to the next step.

[Table 26 s](#page-61-0)hows the minimum SPI writes required to enable the [AD6676.](http://www.analog.com/AD6676?doc=AD6676.pdf) Note the following in the sequence of steps shown in [Table 26:](#page-61-0) 

- The example SPI writes pertain to the following settings:  $F_{ADC} = 3.200$  GHz,  $F_{O} = 250$  MHz, BW = 100 MHz, IDAC1<sub>FS</sub> =  $2$  mA, MRGN\_L = MRGN\_U = 10 MHz, MRGN\_IF = 1 MHz,  $f_{DATA\_IQ} = 200$  MSPS with decimate by 16, and  $f_{REF} =$ 200 MHz with the clock synthesizer enabled.
- Step 3 refers t[o Table 28 f](#page-62-0)or the necessary SPI writes when the clock synthesizer is enabled or disabled, respectively. Example AGC parameters are included in [Table 29 b](#page-62-1)ut are nonessential to device operation.
- The RESON1 calibration for the ADC occurs first with default DEC\_MODE setting. DEC\_MODE is updated to the user specified setting prior to JESD204B calibration.
- ADC and JESD204B calibration and initialization must be successful on first attempt. However, Step 24 and Step 30 are included to provide coverage against external events (supply or clock glitch) that can corrupt this process.

The [AD6676EVB s](http://www.analog.com/AD6676?doc=AD6676.pdf)oftware GUI has an option that automatically generates and saves the series of SPI writes in the .csv file format, as shown in [Table 25,](#page-60-1) which is the preferred method for generating the AD6676 SPI write initialization sequence. Note the following:

- The SPI sequence can be shorter when the [AD6676EVB](http://www.analog.com/AD6676?doc=AD6676.pdf)  development platform is connected to the PC because the software also performs a SPI read back and then only writes to those SPI registers that have been changed from its default setting.
- To generate a SPI initialization sequence for an alternative development platform, ensure that the [AD6676EVB](http://www.analog.com/AD6676?doc=AD6676.pdf) development platform is disconnected from the PC
- When the software GUI is configured for the profile feature, Register 0x115 and Register 0x118 specify the calibration and ADC profile, respectively, that pertain to the specific ADC application parameter settings in Register 0x100 thru Register 0x109 that follow. A SPI write of 0x01 to Register 0x116 follows to initiate the ADC tuning. This process repeats itself for the remaining specified profiles.



<span id="page-60-0"></span>Figure 145. Flowchart for Initialization and Configuration of th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) 

<span id="page-60-1"></span>





<span id="page-61-0"></span>Table 26. SPI Initialization Example,  $f_{CLK} = 3.2$  GHz,  $F_{IF} = 250$  MHz, BW = 100 MHz, IDAC1<sub>FS</sub> = 2 mA, MRGN\_L = MRGN\_U = 10 MHz, **MRGN** IF = 1 MHz,  $f_{\text{DATA-IO}} = 200$  MSPS with Decimate by 16

1 Cells in the Address (Hex) column and Write Value column were left intentionally blank.

# <span id="page-62-2"></span>Table 27. SPI CLK SYN Initialization Example,  $f_{CLK} = 2.94912$  GHz,  $f_{REF} = 122.88$  MHz (Suitable for Decimation by 24)



<span id="page-62-0"></span><sup>1</sup> Cells in the Address (Hex) column and Write Value column were left intentionally blank.

# **Table 28. SPI fCLK Initialization**



# <span id="page-62-1"></span>**Table 29. SPI AGC Initialization Example**



# <span id="page-62-3"></span>**Table 30. SPI Shuffler Initialization Example**



# SERIAL PORT INTERFACE (SPI) **SPI REGISTER MAP DESCRIPTION**

Th[e AD6676 c](http://www.analog.com/AD6676?doc=AD6676.pdf)ontains a set of programmable registers (described in th[e Register Memory Map s](#page-65-2)ection) that initialize and configure the device for its intended application. Note the following points when programming th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) SPI registers:

- Registers pertaining to similar functions are typically grouped together and assigned adjacent addresses.
- Bits that are undefined within a register must be assigned a 0 when writing to that register.
- Do not write to registers that are undefined.
- A hardware or software reset is recommended on powerup to place SPI registers in a known state.

A SPI initialization routine is required as part of the boot process. Se[e Table 26](#page-61-0) for an example procedure.

# **Reset**

Issuing a hardware or software reset places th[e AD6676](http://www.analog.com/AD6676?doc=AD6676.pdf) SPI registers in a known state. Both types of resets are similar in that they place SPI registers to their default states as described in [Table 32,](#page-65-0) with the notable exception that a software reset does not affect Register 0x000. A hardware reset can be issued from a host or external supervisory IC by applying a low pulse with a minimum width of 40 ns to the RESETB pin (Pin G6). RESETB can also kept be left open if unused because it has an internal pull-up resistor. After issuing a reset, the SPI initialization process need only write to registers that are required for the boot process as well as any other register settings that must be modified, depending on the target application.

Although th[e AD6676 d](http://www.analog.com/AD6676?doc=AD6676.pdf)oes feature an internal power on reset (POR), it is still recommended that a software or hardware reset be implemented shortly after power-up. The internal reset signal is derived from a logical OR operation from the internal POR signal, the RESETB pin, and the software reset state. A self clearing software reset can be issued via the reset bit (Register 0x00, Bit 7). It is also recommended that the bit settings for Bits[7:4] be mirrored onto Bits[3:0] for the instruction cycle that issues a software reset.

# **Table 31. SPI Registers Pertaining to SPI Options**



# **SPI OPERATION**

The serial port of th[e AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)hown i[n Figure 146](#page-63-0) has a 3- or 4-wire SPI capability, allowing read/write access to all registers that configure the internal parameters of the device. It provides a flexible, synchronous serial communications port, allowing easy interface to most industry-standard FPGAs and microcontrollers. The 1.8 V to 2.5 V serial input/output is compatible with most synchronous transfer formats.



<span id="page-63-0"></span>The default 4-wire SPI interface consists of a clock (SCLK), serial port enable (CSB), serial data input (SDIO), and serial data output (SDO). The inputs to SCLK, CSB, and SDIO contain a Schmitt trigger centered about VDDIO/2. The maximum frequency for SCLK is 40 MHz. The SDO pin is active only during the transmission of data and remains three-stated at any other time.

A 3-wire SPI interface can be enabled by clearing the SDIO\_DIR bit (Register 0x000, Bit 4). This causes the SDIO pin to become bidirectional such that output data only appears on the SDIO pin during a read operation. The SDO pin remains three-stated in a 3-wire SPI interface.

# **Instruction Header Information**



A 16-bit instruction header must accompany each read and write operation. The MSB is a  $R/\overline{W}$  indicator bit with logic high indicating a read operation. The remaining 15 bits specify the address bits to be accessed during the data transfer portion. The eight data bits immediately follow the instruction header for both read and write operations. For write operations, registers change immediately on writing to the last bit of each transfer byte.

The [AD6676 s](http://www.analog.com/AD6676?doc=AD6676.pdf)erial port can support both most significant bit (MSB) first and least significant bit (LSB) first data formats. [Figure 147](#page-64-0) illustrates how the serial port words are formed for the MSB first and LSB first modes. The bit order is controlled by the LSB\_FIRST bit (Register 0x000, Bit 6). The default value is 0, MSB first. When the LSB\_FIRST bit is set high, the serial port interprets both instruction and data byte LSBs first.



Figure 147. SPI Timing, MSB First (Upper) and LSB First (Lower)

<span id="page-64-0"></span>[Figure 148](#page-64-1) illustrates the timing requirements for a write operation to the SPI port. After the serial port enable (CSB) signal goes low, data (SDIO) pertaining to the instruction header is read on the rising edges of the clock (SCLK). To initiate a write operation, the read/not write bit is set low. After the instruction header is read, the eight data bits pertaining to

the specified register are shifted into the SDIO pin on the rising edge of the next eight clock cycles.

[Figure 149](#page-64-2) illustrates the timing for a 3-wire read operation to the SPI port. After CSB goes low, data (SDIO) pertaining to the instruction header is read on the rising edges of SCLK. A read operation occurs if the read/not write indicator is set high. After the address bits of the instruction header are read, the eight data bits pertaining to the specified register are shifted out of the SDIO pin on the falling edges of the next eight clock cycles.

[Figure 150](#page-64-3) illustrates the timing for a 4-wire read operation to the SPI port. The timing is similar to the 3-wire read operation with the exception that data appears at the SDO pin only, whereas the SDIO pin remains at high impedance throughout the operation. The SDO pin is an active output only during the data transfer phase and remains three-stated at all other times.

Lastly, the SPI port must not be active during periods when the full dynamic performance of the converter is required. Because the SCLK, CSB, and SDIO signals are typically asynchronous to the ADC clock, noise from these signals can degrade converter performance. If the on-board SPI bus is used for other devices, it may be necessary to provide buffers between this bus and the [AD6676 t](http://www.analog.com/AD6676?doc=AD6676.pdf)o keep these signals from transitioning at the converter input pins and causing unwanted spurious signals.

<span id="page-64-2"></span><span id="page-64-1"></span>

<span id="page-64-3"></span>Figure 150. SPI 4-Wire Read Operation Timing

# <span id="page-65-2"></span>REGISTER MEMORY MAP AND DETAILS

# <span id="page-65-1"></span>**REGISTER MEMORY MAP**

Note that all address and bit locations that are not included i[n Table 32](#page-65-0) are not currently supported for this device.

# <span id="page-65-0"></span>**Table 32. Register Summary**





# **REGISTER DETAILS**

## **SPI Configuration Register**

**Address: 0x000, Reset: 0x18, Name: SPI\_CONFIG**

# **Table 33. Bit Descriptions for SPI\_CONFIG**



This register uses the first four bits to configure SPI interface/format thus Bit 0, Bit 1, and Bit 3 are mirror images of Bit 7, Bit 6, and Bit 4.

# **Device Configuration Register**

# **Address: 0x002, Reset: 0x00, Name: DEVICE\_CONFIG**

# **Table 34. Bit Descriptions for DEVICE\_CONFIG**



# **Chip Type Register**

**Address: 0x003, Reset: 0x03, Name: CHIP\_TYPE**

### **Table 35. Bit Descriptions for CHIP\_TYPE**



# **Chip ID 0 Register**

### **Address: 0x004, Reset: 0xBB, Name: CHIP\_ID0**

# **Table 36. Bit Descriptions for CHIP\_ID0**



# **Chip ID 1 Register**

# **Address: 0x005, Reset: 0x00, Name: CHIP\_ID1**

# **Table 37. Bit Descriptions for CHIP\_ID1**



# **Chip Grade/Revision Register**

**Address: 0x006, Reset: 0x00, Name: GRADE\_REVISION**

# **Table 38. Bit Descriptions for GRADE\_REVISION**



### **Vendor ID 0 Register**

**Address: 0x00C, Reset: 0x56, Name: VENDOR\_ID0**

### **Table 39. Bit Descriptions for VENDOR\_ID0**



## **Vendor ID 1 Register**

**Address: 0x00D, Reset: 0x04, Name: VENDOR\_ID1**

### **Table 40. Bit Descriptions for VENDOR\_ID1**



# **ADC CLK Frequency LSB Register**

**Address: 0x100, Reset: 0x10, Name: FADC\_0**

### **Table 41. Bit Descriptions for FADC\_0**



## **ADC CLK Frequency MSB Register 1**

# **Address: 0x101, Reset: 0x0E, Name: FADC\_1**

### **Table 42. Bit Descriptions for FADC\_1**



### **IF Frequency LSB Register 0**

**Address: 0x102, Reset: 0x2C, Name: FIF\_0**

### **Table 43. Bit Descriptions for FIF\_0**



### **IF Frequency MSB Register 1**

## **Address: 0x103, Reset: 0x01, Name: FIF\_1**

# **Table 44. Bit Descriptions for F0\_1**



# **BW LSB Register 0**

**Address: 0x104, Reset: 0x3C, Name: BW\_0**

### **Table 45. Bit Descriptions for BW\_0**



# **BW MSB Register 1**

**Address: 0x105, Reset: 0x00, Name: BW\_1**

# **Table 46. Bit Descriptions for BW\_1**



# **External Inductance Value Register**

# **Address: 0x106, Reset: 0x14, Name: LEXT**

### **Table 47. Bit Descriptions for LEXT**



### **Bandwidth Margin (Low End) Register**

## **Address: 0x107, Reset: 0x05, Name: MRGN\_L**

# **Table 48. Bit Descriptions for MRGN\_L**



### **Bandwidth Margin (Upper End) Register**

**Address: 0x108, Reset: 0x05, Name: MRGN\_U**

# **Table 49. Bit Descriptions for MRGN\_U**



### **Bandwidth Margin (IF) Register**

# **Address: 0x109, Reset: 0x00, Name: MRGN\_IF**

### **Table 50. Bit Descriptions for MRGN\_IF**



# **IDAC1FS Gain Scaling Register**

**Address: 0x10A, Reset: 0x40, Name: IDAC1\_FS**

# **Table 51. Bit Descriptions for IDAC1\_FS**



# **Calibration Control Register**

**Address: 0x115, Reset: 0x00, Name: CAL\_CTRL**

### **Table 52. Bit Descriptions for CAL\_CTRL**



## **Calibration Command Register**

### **Address: 0x116, Reset: 0x00, Name: CAL\_CMD**

### **Table 53. Bit Descriptions for CAL\_CMD**



Setting a 1 in one or more of the bits in this register initiates the internal calibration. This register is cleared automatically at the end of calibration or by setting the FORCE\_END\_CAL bit.

# **Calibration Done Register**

**Address: 0x117, Reset: 0x00, Name: CAL\_DONE**

### **Table 54. Bit Descriptions for ADC\_PROFILE**



# **ADC Profile Selection Register**

**Address: 0x118, Reset: 0x00, Name: ADC\_PROFILE**

### **Table 55. Bit Descriptions for ADC\_PROFILE**



# **Force End of Calibration Register**

**Address: 0x11A, Reset: 0x00, Name: FORCE\_END\_CAL**

# **Table 56. Bit Descriptions for FORCE\_END\_CAL**



This is a user accessible SPI register only when the controller is performing a calibration.

### **Decimation Mode Register**

**Address: 0x140, Reset: 0x01, Name: DEC\_MODE**

### **Table 57. Bit Descriptions for DEC\_MODE**



## **Coarse NCO Tuning Register**

**Address: 0x141, Reset: 0x05, Name: MIX1\_TUNING**

## **Table 58. Bit Descriptions for MIX1\_TUNING**



This register has four copies, one for each of the ADC profiles. The default for Profile 0 is 0x05; the default for the other profiles is 0x00. At the default ADC clock rate of 3.2 GHz; the default Profile 0 downconversion frequency is  $(5/64) \times 3.6$  GHz = 250 MHz
## **Fine NCO Tuning Register**

**Address: 0x142, Reset: 0x15, Name: MIX2\_TUNING**

#### **Table 59. Bit Descriptions for MIX2\_TUNING**



This register has four copies, one for each of the ADC profiles. The default for Profile 0 is 0x21; the default for the other profiles is 0x00. At the default ADC clock rate of 3.2 GHz, the default Profile 0 downconversion frequency is (33/4096) × 3.2 GHz = 25.78125 MHz

#### **Coarse NCO Initial Phase Register**

#### **Address: 0x143, Reset: 0x00, Name: MIX1\_INIT**

#### **Table 60. Bit Descriptions for MIX1\_INIT**



This register has four copies, one for each of the ADC profiles. The default for Profile 0 is 0x00.

#### **Fine NCO Initial Phase LSB Register**

**Address: 0x144, Reset: 0x00, Name: MIX2\_INIT\_LSB**

#### **Table 61. Bit Descriptions for MIX2\_INIT\_LSB**



This register has four copies, one for each of the ADC profiles. The default for Profile 0 is 0x00.

#### **Fine NCO Initial Phase MSB Register**

#### **Address: 0x145, Reset: 0x00, Name: MIX2\_INIT\_MSB**

## **Table 62. Bit Descriptions for MIX2\_INIT\_MSB**



This register has four copies, one for each of the ADC profiles. The default for Profile 0 is 0x00.

#### **Datapath Controls Register**

#### **Address: 0x146, Reset: 0x00, Name: DP\_CTRL**

#### **Table 63. Bit Descriptions for DP\_CTRL**



## **Standby Register**

## **Address: 0x150, Reset: 0x02, Name: STANDBY**

When bits in this register are set, the corresponding blocks enter a power-down state when the chip enters standby mode.



## **Table 64. Bit Descriptions for STANDBY**

## **Digital Power-Down Register**

## **Address: 0x151, Reset: 0x00, Name: PD\_DIG**

#### **Table 65. Bit Descriptions for PD\_DIG**



## **Standby Pin Control Register**

**Address: 0x152, Reset: 0x00, Name: PD\_PIN\_CTRL**

#### **Table 66. Bit Descriptions for PD\_PIN\_CTRL**



## **Attenuator Mode Register**

## **Address: 0x180, Reset: 0x00, Name: ATTEN\_MODE**

## **Table 67. Bit Descriptions for ATTEN\_MODE**



## **Attenuator AGC2 Pin Low Value Register**

## **Address: 0x181, Reset: 0x0C, Name: ATTEN\_VALUE\_PIN0**

## **Table 68. Bit Descriptions for ATTEN\_VALUE\_PIN1**



## **Attenuator AGC2 Pin High Value Register**

#### **Address: 0x182, Reset: 0x0C, Name: ATTEN\_VALUE\_PIN1**

#### **Table 69. Bit Descriptions for ATTEN\_VALUE\_PIN1**



## **Attenuator Initialization Register**

#### **Address: 0x183, Reset: 0x00, Name: ATTEN\_INIT**

#### **Table 70. Bit Descriptions for ATTEN\_INIT**



#### **Attenuator Status Register**

**Address: 0x184, Reset: 0x0C, Name: ATTEN\_CTL**

#### **Table 71. Bit Descriptions for ATTEN\_CTL**



#### **ADC Reset Threshold Register**

**Address: 0x188, Reset: 0x05, Name: ADCRE\_THRH**

#### **Table 72. Bit Descriptions for ADCRE\_THRH**



#### **ADC Reset Pulse Length Register**

**Address: 0x189, Reset: 0x01, Name: ADCRE\_PULSE\_LEN**

#### **Table 73. Bit Descriptions for ADCRE\_PULSE\_LEN**



## **ADC Reset Attenuation Step Register**

**Address: 0x18A, Reset: 0x06, Name: ATTEN\_STEP\_RE**

#### **Table 74. Bit Descriptions for ATTEN\_STEP\_RE**



#### **ADC Unstable Flag Control Register**

#### **Address: 0x18F, Reset: 0x00, Name: ADC\_UNSTABLE**

#### **Table 75. Bit Descriptions for ADC\_UNSTABLE**



#### **Peak Threshold 0 LSB Register**

#### **Address: 0x193, Reset: 0x00, Name: PKTHRH0\_LSB**

#### **Table 76. Bit Descriptions for PKTHRH0\_LSB**



#### **Peak Threshold 0 MSB Register**

#### **Address: 0x194, Reset: 0x00, Name: PKTHRH0\_MSB**

#### **Table 77. Bit Descriptions for PKTHRH0\_MSB**



## **Peak Threshold 1 LSB Register**

**Address: 0x195, Reset: 0x00, Name: PKTHRH1\_LSB**

#### **Table 78. Bit Descriptions for PKTHRH1\_LSB**



#### **Peak Threshold 1 MSB Register**

**Address: 0x196, Reset: 0x00, Name: PKTHRH1\_MSB**

#### **Table 79. Bit Descriptions for PKTHRH1\_MSB**



## **DEC Low Threshold LSB Register**

**Address: 0x197, Reset: 0x00, Name: LOWTHRH\_LSB**

#### **Table 80. Bit Descriptions for LOWTHRH\_LSB**



## **Low Threshold MSB Register**

**Address: 0x198, Reset: 0x00, Name: LOWTHRH\_MSB**

#### **Table 81. Bit Descriptions for LOWTHRH\_MSB**



#### **Dwell Time Mantissa Register**

**Address: 0x199, Reset: 0x00, Name: DWELL\_TIME\_MANTISSA**

#### **Table 82. Bit Descriptions for DWELL\_TIME\_MANTISSA**



#### **Dwell Time Exponent Register**

**Address: 0x19A, Reset: 0x00, Name: DWELL\_TIME\_EXP**

#### **Table 83. Bit Descriptions for DWELL\_TIME\_EXP**



## **AGC Flag 0 Select Register**

**Address: 0x19B, Reset: 0x00, Name: FLAG0\_SEL**





## **AGC Flag 1 Select Register**

**Address: 0x19C, Reset: 0x00, Name: FLAG1\_SEL**

## **Table 85. Bit Descriptions for FLAG1\_SEL**



## **AGC Flag Enable Register**

**Address: 0x19E, Reset: 0x00, Name: EN\_FLAG**

**Table 86. Bit Descriptions for EN\_FLAG** 



## **Force GPIO Register**

## **Address: 0x1B0, Reset: 0x00, Name: FORCE\_GPIO**

## **Table 87. Bit Descriptions for FORCE\_GPIO**



## **Force GPIO as Output Register**

**Address: 0x1B1, Reset: 0x00, Name: FORCE\_GPIO\_OUT**

## **Table 88. Bit Descriptions for FORCE\_GPIO\_OUT**



## **Force GPIO Value Register**

**Address: 0x1B2, Reset: 0x00, Name: FORCE\_GPIO\_VAL**

## **Table 89. Bit Descriptions for FORCE\_GPIO\_VAL**



## **GPIO Output Status Register**

#### **Address: 0x1B3, Reset: 0x00, Name: READ\_GPO**

## **Table 90. Bit Descriptions for READ\_GPO**



## **GPIO Input Status Register**

**Address: 0x1B4, Reset: 0x00, Name: READ\_GPI**

#### **Table 91. Bit Descriptions for READ\_GPI**



## **JESD204 DID Register**

**Address: 0x1C0, Reset: 0x00, Name: DID**

#### **Table 92. Bit Descriptions for DID**



## **JESD204 BID Register**

**Address: 0x1C1, Reset: 0x00, Name: BID**

## **Table 93. Bit Descriptions for BID**



## **JESD204 L/SCR Register**

**Address: 0x1C3, Reset: 0x00, Name: L**

#### **Table 94. Bit Descriptions for L**





## **JESD204 F Register**

**Address: 0x1C4, Reset: 0x03, Name: F**

## **Table 95. Bit Descriptions for F**



## **JESD204 K Register**

**Address: 0x1C5, Reset: 0x1F, Name: K**

#### **Table 96. Bit Descriptions for K**



## **JESD204 M Register**

**Address: 0x1C6, Reset: 0x01, Name: M**

#### **Table 97. Bit Descriptions for M**



## **JESD204 S Register**

**Address: 0x1C9, Reset: 0x00, Name: S**

#### **Table 98. Bit Descriptions for S**



## **JESD204 RES1 Register**

**Address: 0x1CB, Reset: 0x00, Name: RES1**

#### **Table 99. Bit Descriptions for RES1**



## **JESD204 RES2 Register**

**Address: 0x1CC, Reset: 0x00, Name: RES2**

## **Table 100. Bit Descriptions for RES2**



## **JESD204 LID0 Register**

**Address: 0x1D0, Reset: 0x00, Name: LID0**

#### **Table 101. Bit Descriptions for LID0**



## **JESD204 LID1 Register**

**Address: 0x1D1, Reset: 0x01, Name: LID1**

#### **Table 102. Bit Descriptions for LID1**



#### **JESD204 FCHK0 Register**

**Address: 0x1D8, Reset: 0x44, Name: FCHK0**

#### **Table 103. Bit Descriptions for FCHK0**



#### **JESD204 FCHK1 Register**

#### **Address: 0x1D9, Reset: 0x45, Name: FCHK1**

**Table 104. Bit Descriptions for FCHK1** 



#### **Enable Lane FIFO Register**

**Address: 0x1E0, Reset: 0x00, Name: EN\_LFIFO**

## **Table 105. Bit Descriptions for EN\_LFIFO**



## **Swap Register**

**Address: 0x1E1, Reset: 0x00, Name: SWAP**

#### **Table 106. Bit Descriptions for SWAP**



## **Link/Lane Power-Down Register**

**Address: 0x1E2, Reset: 0x00, Name: LANE\_PD**

## **Table 107. Bit Descriptions for LANE\_PD**



## **Interface Control 0 Register**

**Address: 0x1E3, Reset: 0x14, Name: MIS1**

## **Table 108. Bit Descriptions for MIS1**



## **Interface Control 1 Register**

**Address: 0x1E4, Reset: 0x00, Name: SYNC\_PIN**

## **Table 109. Bit Descriptions for SYNC\_PIN**



## **Interface Test Register**

**Address: 0x1E5, Reset: 0x00, Name: TEST\_GEN**

## **Table 110. Bit Descriptions for TEST\_GEN**



## **ILAS Count Register**

**Address: 0x1E6, Reset: 0x00, Name: KF\_ILAS**

## **Table 111. Bit Descriptions for KF\_ILAS**



## **SYNCINB and SYSREF Control Register**

**Address: 0x1E7, Reset: 0x00, Name: SYNCINB\_CTRL**

## **Table 112. Bit Descriptions for SYNCB\_CTRL**



## **Clock Synchronization Register**

**Address: 0x1E8, Reset: 0x00, Name: MIX\_CTRL**

#### **Table 113. Bit Descriptions for MIX\_CTRL**



## **LMFC Offset Register**

## **Address: 0x1E9, Reset: 0x00, Name: K\_OFFSET**

#### **Table 114. Bit Descriptions for K\_OFFSET**



## **SYSREF Window Register**

**Address: 0x1EA, Reset: 0x00, Name: SYSREF**

## **Table 115. Bit Descriptions for SYSREF**



## **PHY Control 0 Register**

**Address: 0x1EB, Reset: 0x1C, Name: SER1**





## **PHY Control 1 Register**

**Address: 0x1EC, Reset: 0x00, Name: SER2**

#### **Table 117. Bit Descriptions for SER1**



## **PHY Control 3 Register**

## **Address: 0x1EF, Reset: 0x00, Name: PRE-EMPHASIS**

## **Table 118. Bit Descriptions for PRE-EMPHASIS**



## **ADC Standby 0 Register**

**Address: 0x250, Reset: 0xFF, Name: STBY\_DAC**

## **Table 119. Bit Descriptions for STBY\_DAC**



## **CLKSYN Enable Register**

**Address: 0x2A0, Reset: 0x00, Name: CLKSYN\_ENABLE**





## **CLKSYN Integer N LSB Register**

#### **Address: 0x2A1, Reset: 0x80, Name: CLKSYN\_INT\_N\_LSB**

## **Table 121. Bit Descriptions for CLKSYN\_INT\_N\_LSB**



## **CLKSYN Integer N MSB Register**

#### **Address: 0x2A2, Reset: 0x00, Name: CLKSYN\_INT\_N\_MSB**

## **Table 122. Bit Descriptions for CLKSYN\_INT\_N\_MSB**



#### **CLKSYN VCO Calibration RESET Register**

#### **Address: 0x2A5, Reset: 0x00, Name: VCO\_CAL\_RESET**

## **Table 123. Bit Descriptions for VCO\_CAL\_RESET**



#### **CLKSYN KVCO VCO Register**

#### **Address: 0x2A9, Reset: 0x00, Name: CLKSYN\_KVCO**

#### **Table 124. Bit Descriptions for CLKSYN\_KVCO**



## **CLKSYN VCO Bias Register**

**Address: 0x2AA, Reset: 0x37, Name: CLKSYN\_VCO\_BIAS**



## **Table 125. Bit Descriptions for CLKSYN\_VCO\_BIAS**

## **CLKSYN VCO Calibration Register**

**Address: 0x2AB, Reset: 0xC0, Name: CLKSYN\_VCO\_CAL**

#### **Table 126. Bit Descriptions for CLKSYN\_VCO\_CAL**



## **CLKSYN Charge Pump Register**

**Address: 0x2AC, Reset: 0x19, Name: CLKSYN\_I\_CP**

## **Table 127. Bit Descriptions for CLKSYN\_I\_CP**



## **CLKSYN Charge Pump Calibration Register**

**Address: 0x2AD, Reset: 0x00, Name: EN\_CP\_CAL**

## **Table 128. Bit Descriptions for EN\_CP\_CAL**



## **CLKSYN VCO Varactor Register**

**Address: 0x2B7, Reset: 0xD0, Name: CLKSYN\_VCO\_VAR**

#### **Table 129. Bit Descriptions for CLKSYN\_VCO\_VAR**



## **CLKSYN Reference Divider and SYSREF Control Register**

**Address: 0x2BB, Reset: 0xB9, Name: CLKSYN\_R\_DIV**

## **Table 130. Bit Descriptions for CLKSYN\_R\_DIV**



## **CLKSYN Status Register**

## **Address: 0x2BC, Reset: 0x80, Name: CLKSYN\_STATUS**

## **Table 131. Bit Descriptions for CLKSYN\_STATUS**



#### **JESDSYN Status Register**

## **Address: 0x2DC, Reset: 0x80, Name: JESDSYN\_STATUS**

## **Table 132. Bit Descriptions for JESDSYN\_STATUS**



## **Shuffler Control Register**

**Address: 0x340, Reset: 0x03, Name: SHUFFLE\_CTRL**

## **Table 133. Bit Descriptions for SHUFFLE\_CTRL**



## **Shuffler Threshold 1 and 2 Register**

**Address: 0x342, Reset: 0xF5, Name: SHUFFLE\_THREG\_0**



## **Table 134. Bit Descriptions for SHUFFLE\_THREG\_0**

## **Shuffler Threshold 3 and 4 Register**

**Address: 0x343, Reset: 0xFF, Name: SHUFFLE\_THREG\_1**

## **Table 135. Bit Descriptions for SHUFFLE\_THREG\_1**



# OUTLINE DIMENSIONS



Dimensions shown in millimeters

## **ORDERING GUIDE**



 $1 Z =$  RoHS Compliant Part.

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